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Kim

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(54) **LIQUID CRYSTAL DISPLAY AND TEST METHOD THEREOF**

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Jun. 2, 2005 (KR) 10-2005-0047262

(51) **Int. Cl.**
G02F 1/1333 (2006.01)

(52) **U.S. Cl.** 349/40; 324/770; 349/54

(58) **Field of Classification Search** 349/40;
324/770

See application file for complete search history.

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(57) **ABSTRACT**

A liquid crystal display includes a plurality of pixel electrodes arranged in a matrix and having first and second sub-pixel electrodes differentiated in size from each other. First and second switching elements are connected to the first and second sub-pixel electrodes, respectively. First and second gate lines are connected to the first and second switching elements, respectively. A data line is connected to the first and second switching elements to transmit a data voltage. First and second gate shorting bars are connected to the first and second gate lines, respectively. The gate lines connected to the respective sub-pixels are connected to two or four gate shorting bars to allow an array test and a visual inspection test, and to thereby detect a bridge between respective sub-pixel electrode neighbors in a simplified manner.

24 Claims, 19 Drawing Sheets

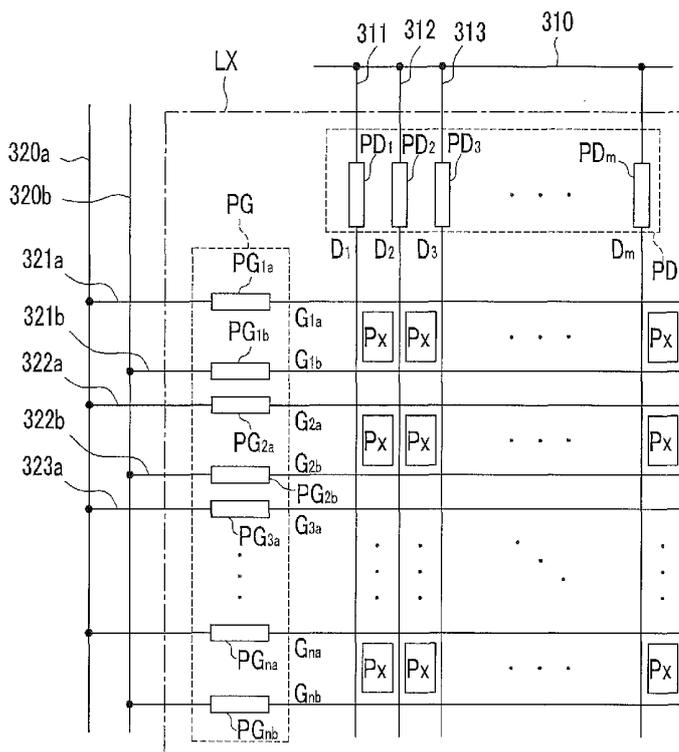


FIG.1

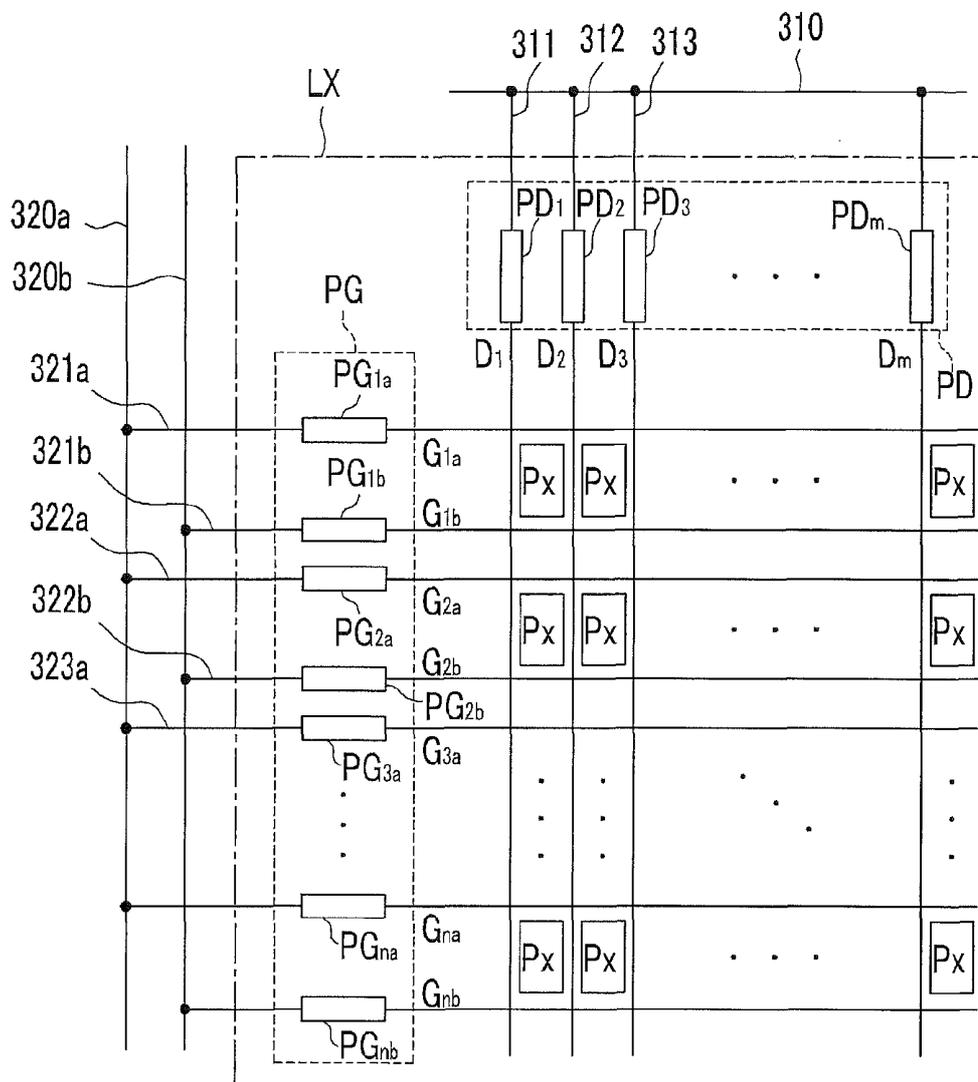


FIG.2

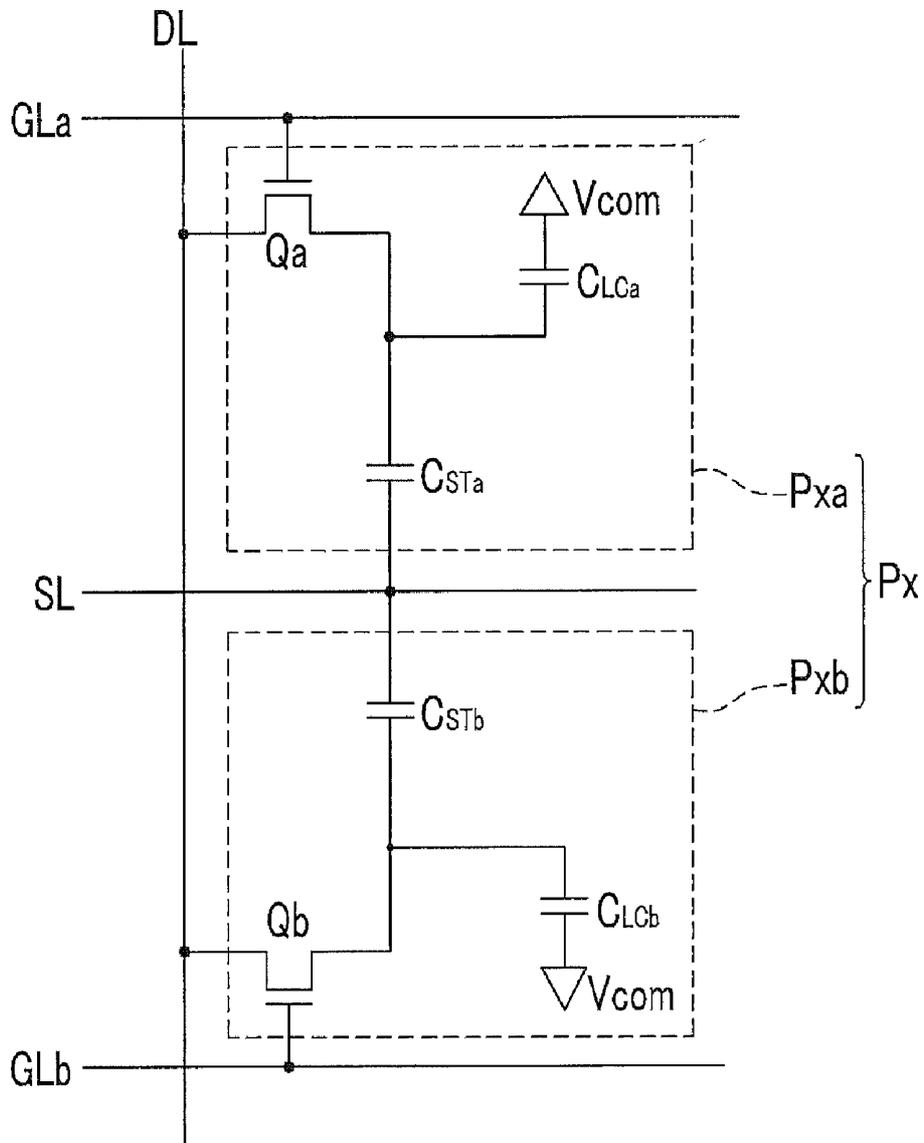


FIG.3

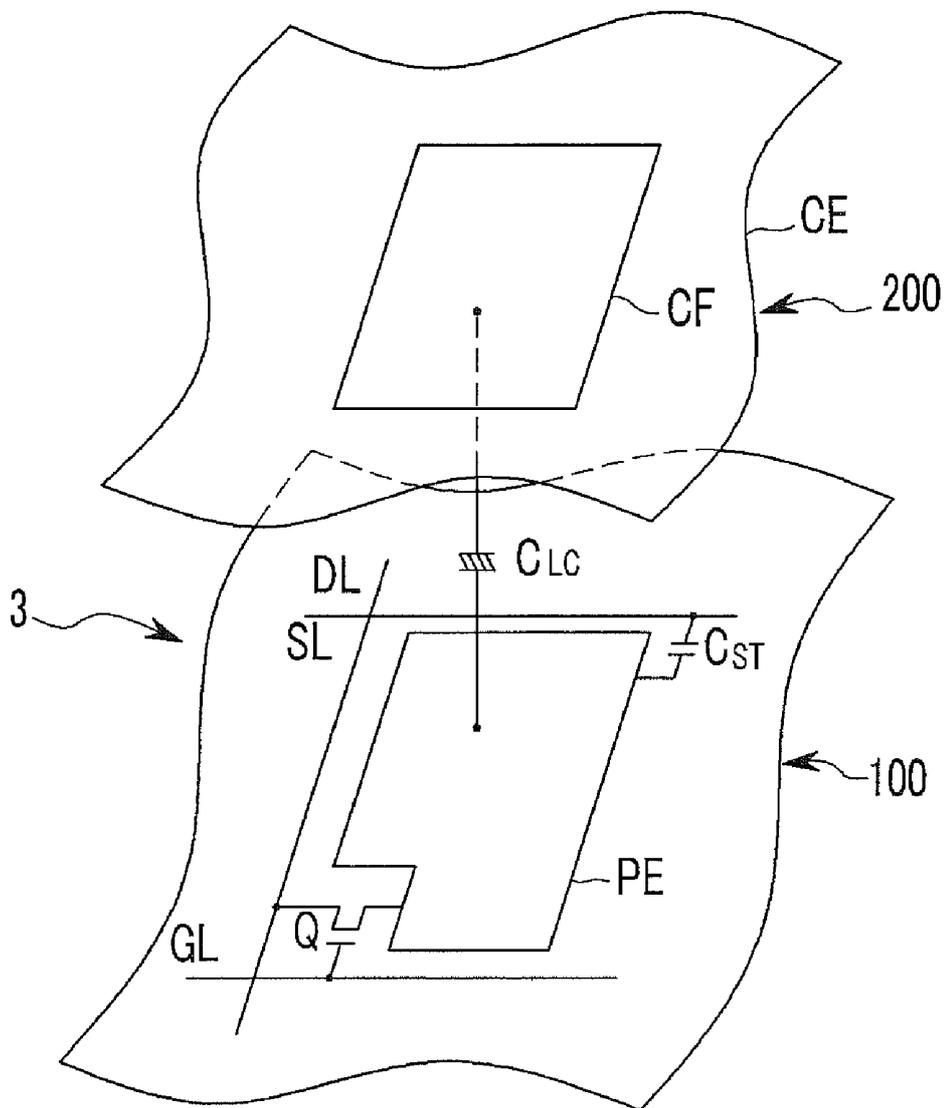


FIG. 4

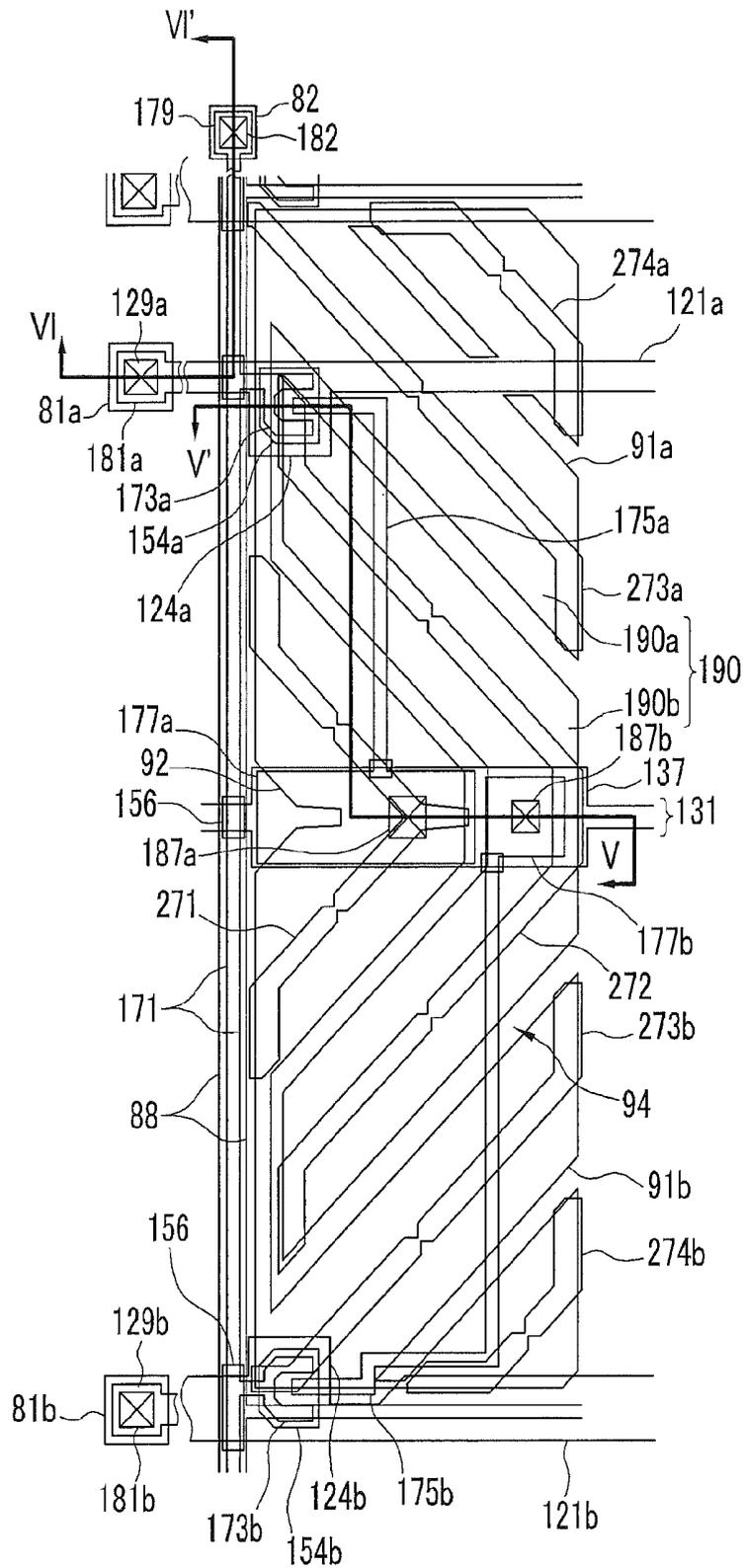


FIG. 5

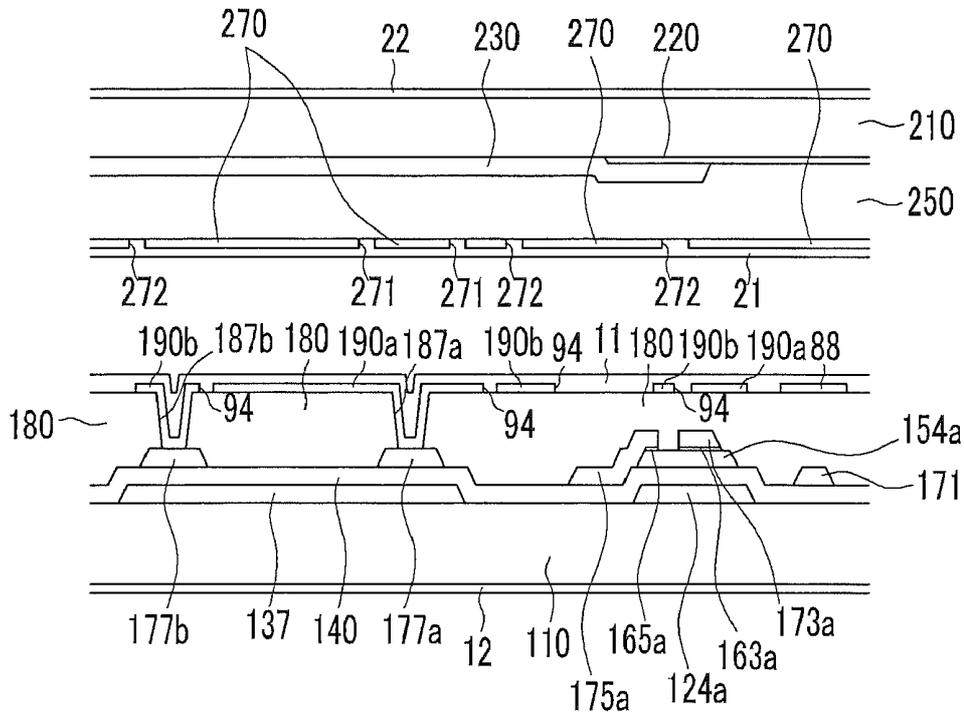


FIG. 6

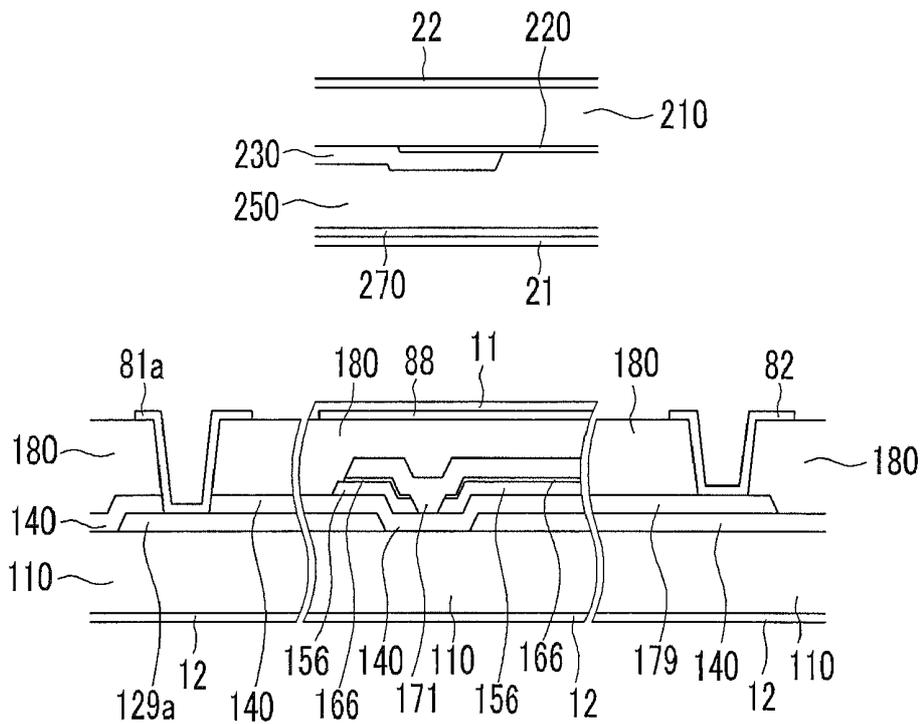


FIG. 8

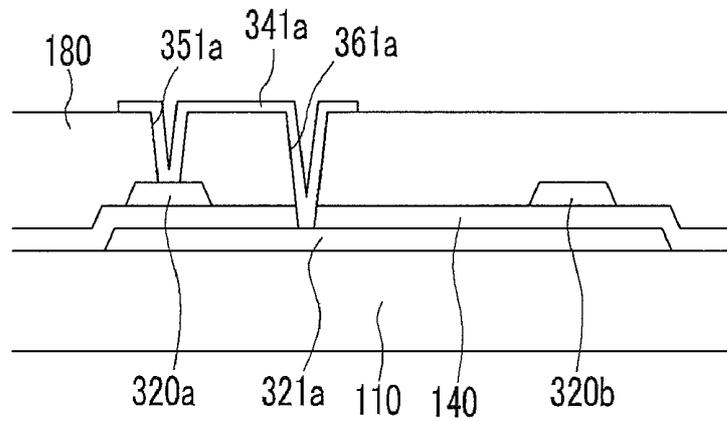


FIG. 9

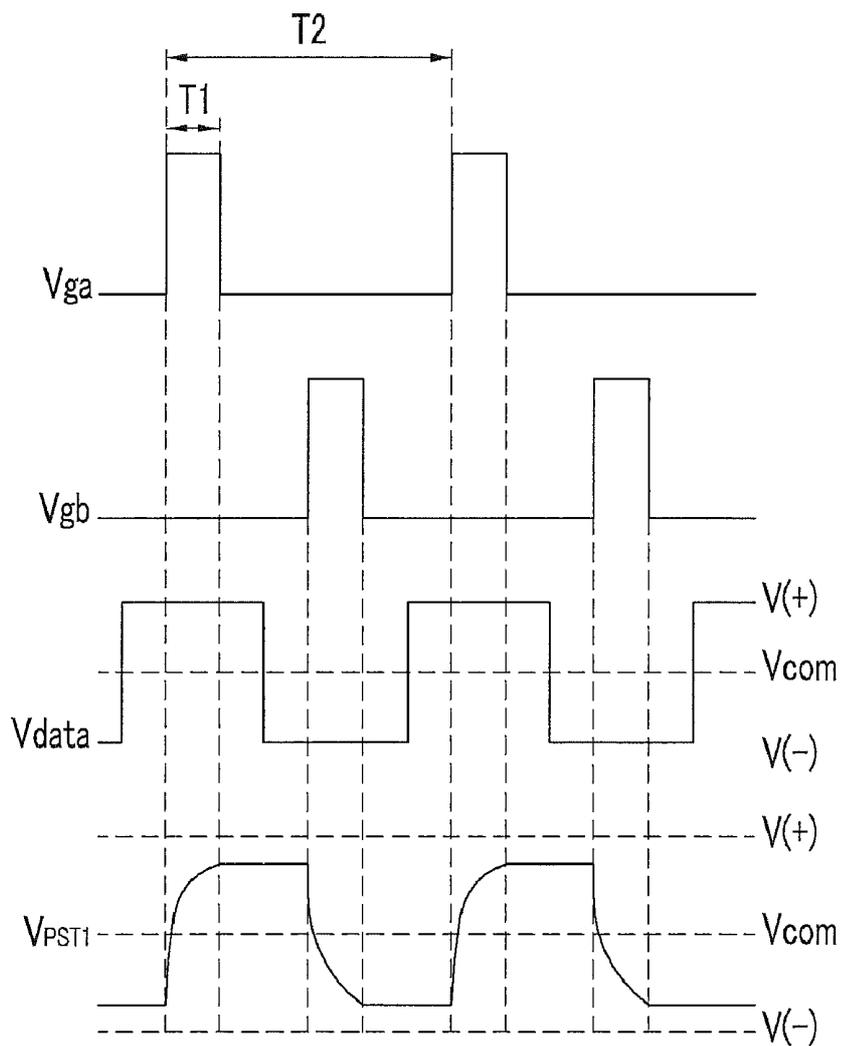


FIG.12

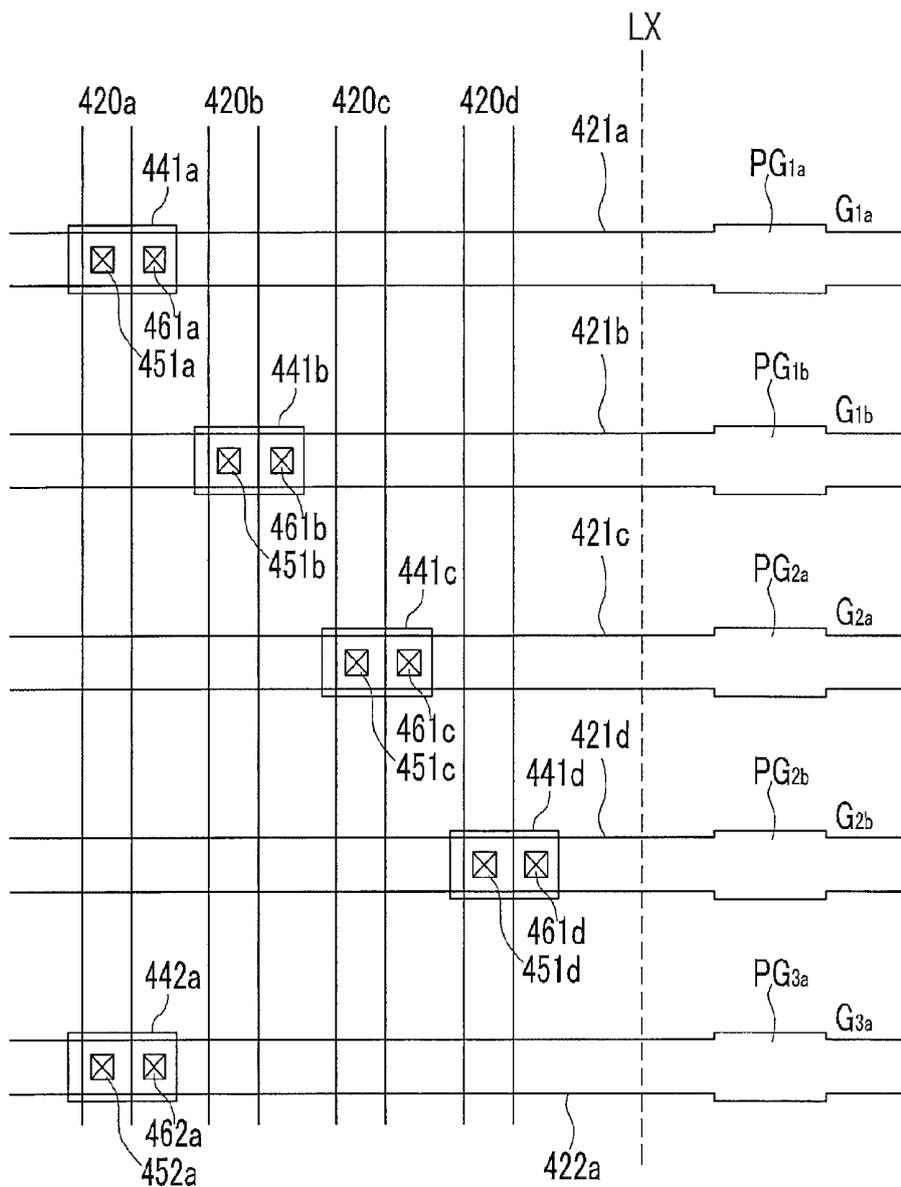


FIG. 13

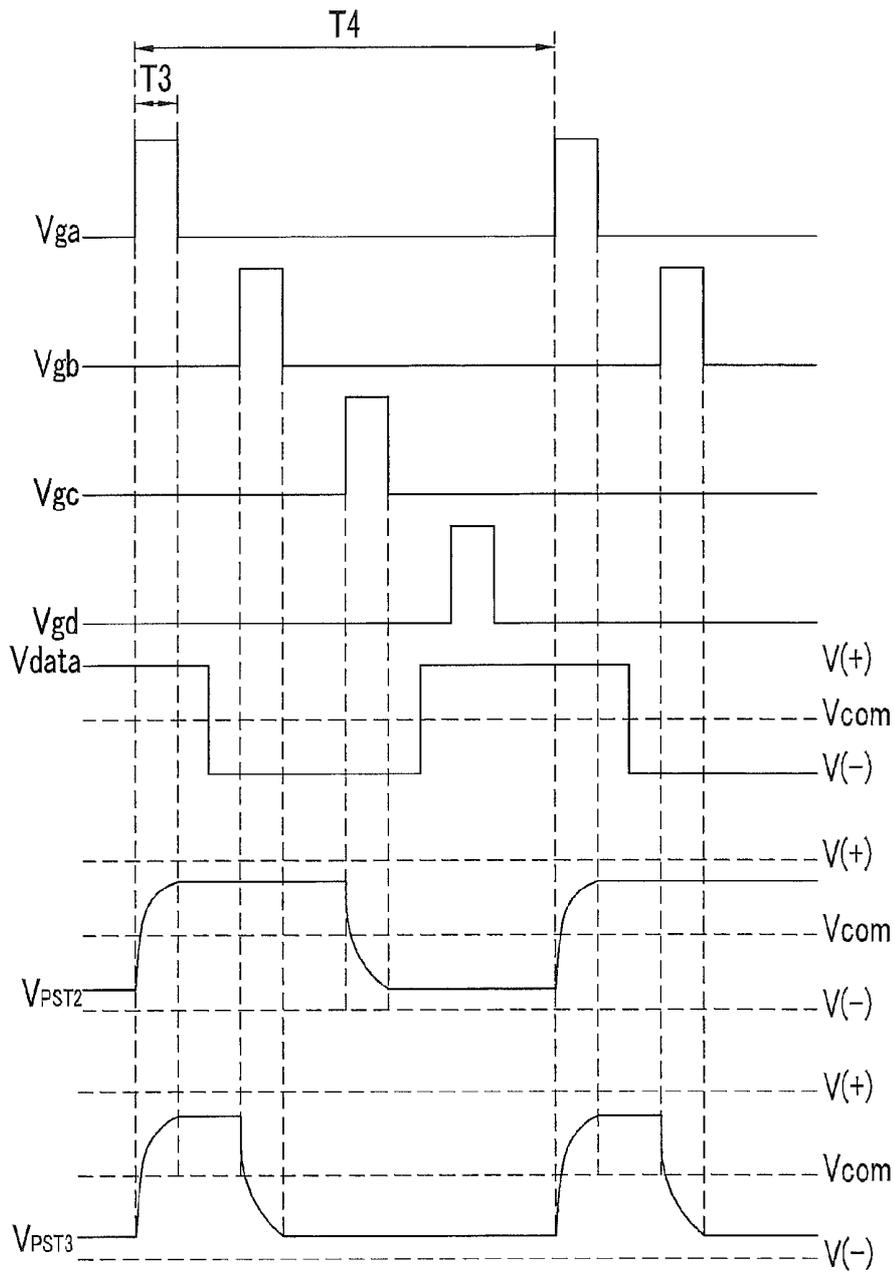


FIG. 14

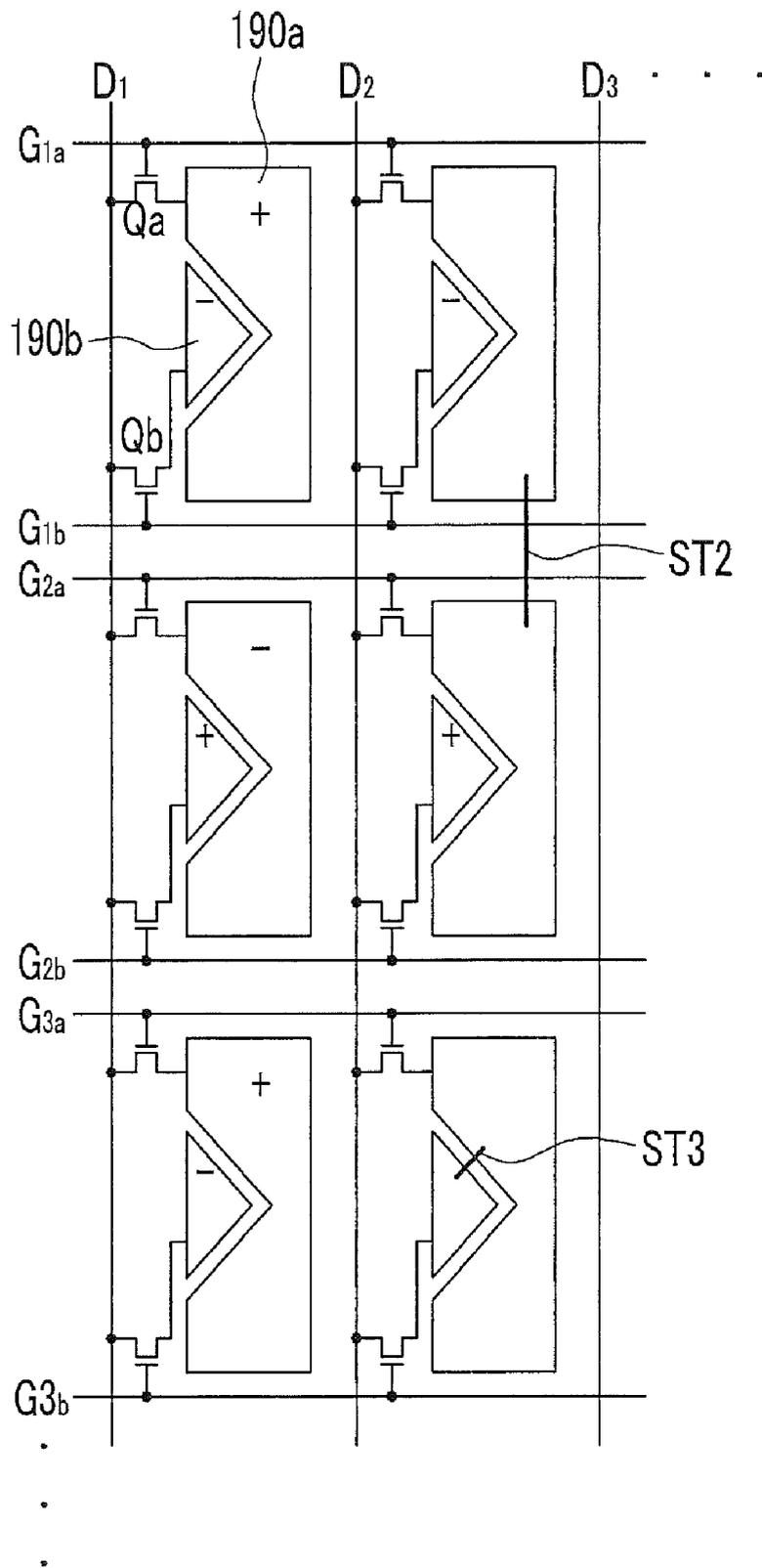


FIG. 15

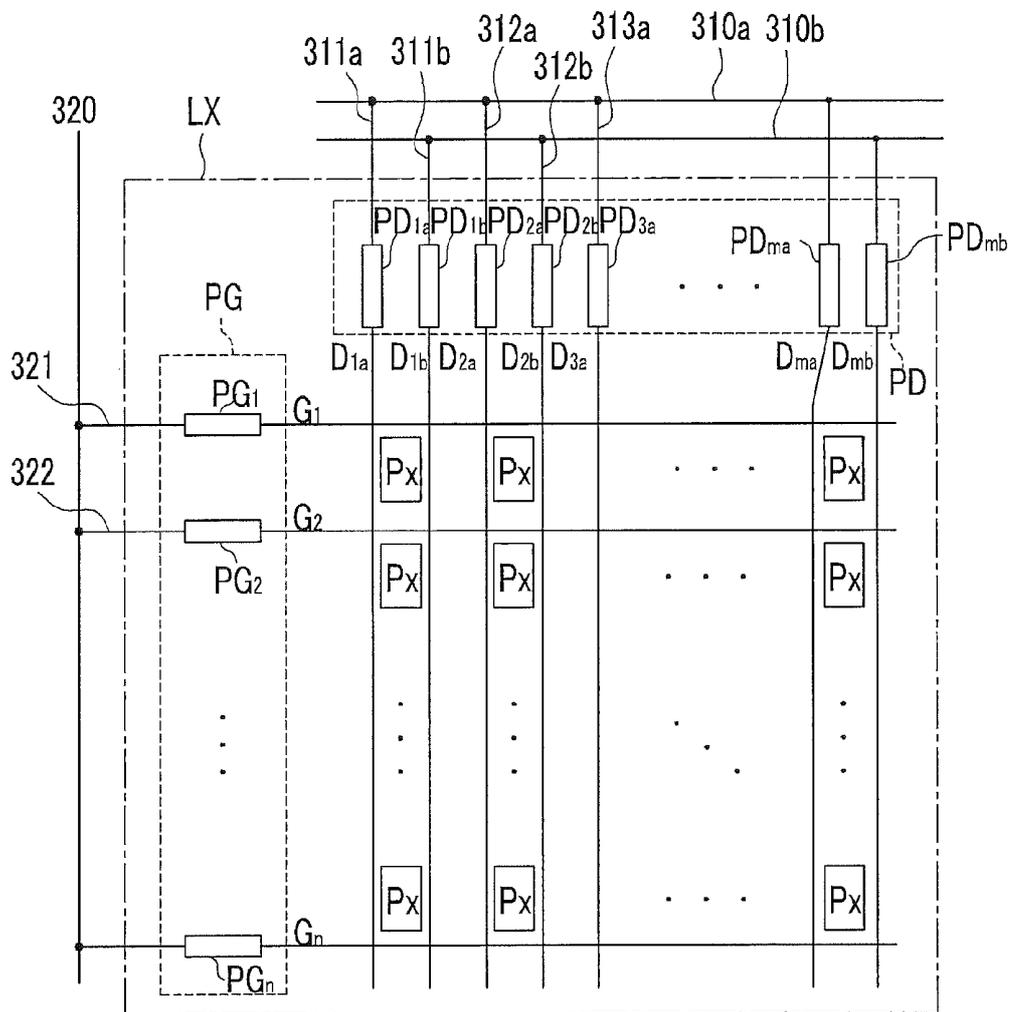


FIG. 17

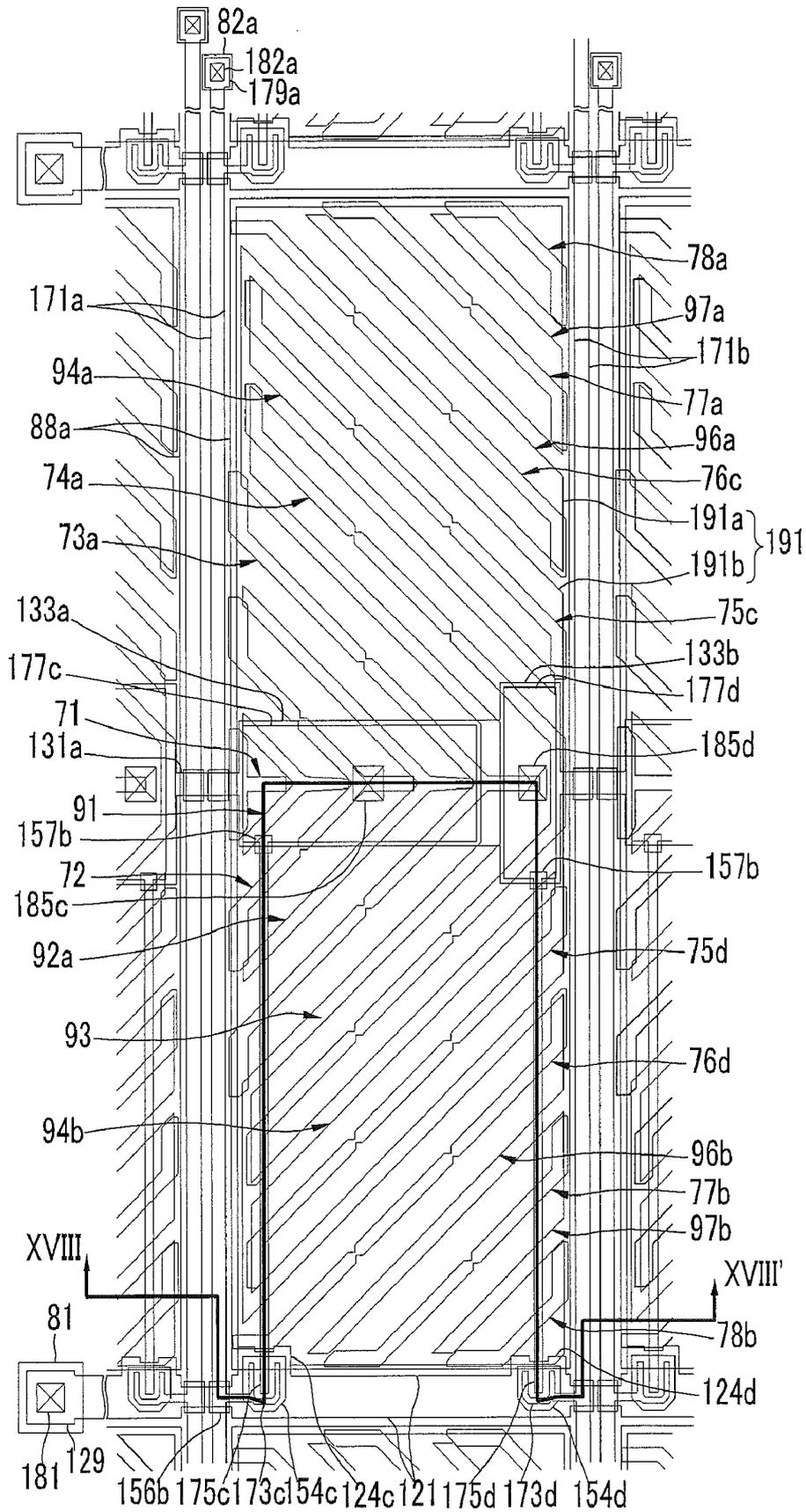


FIG. 18

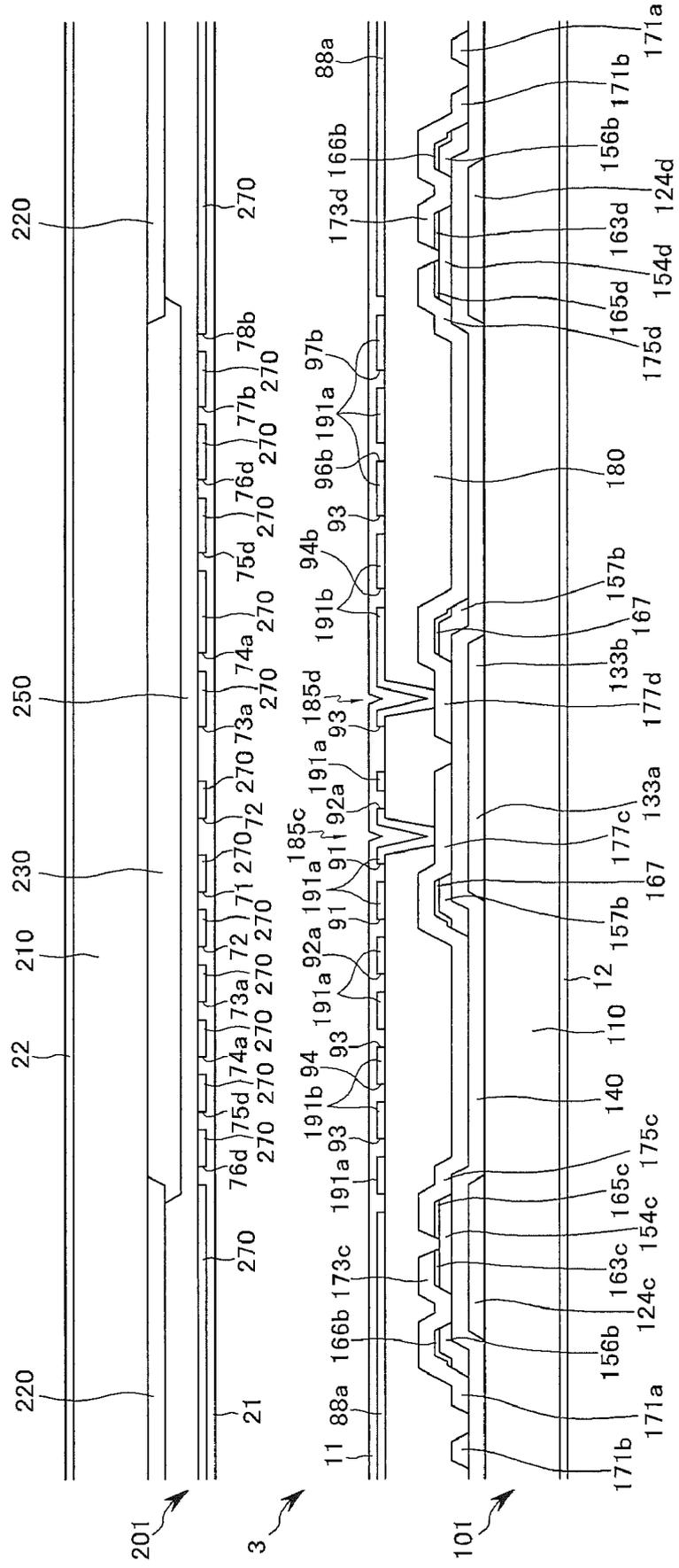


FIG. 19

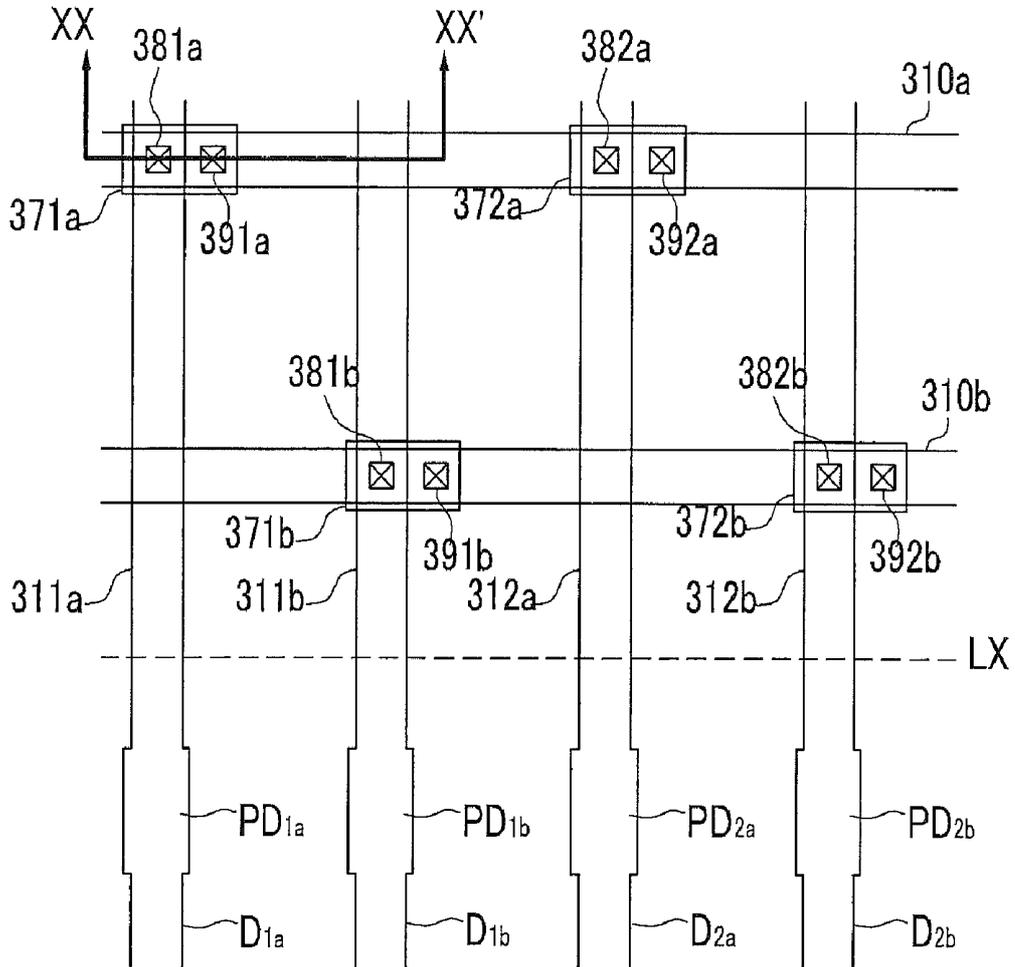


FIG. 20

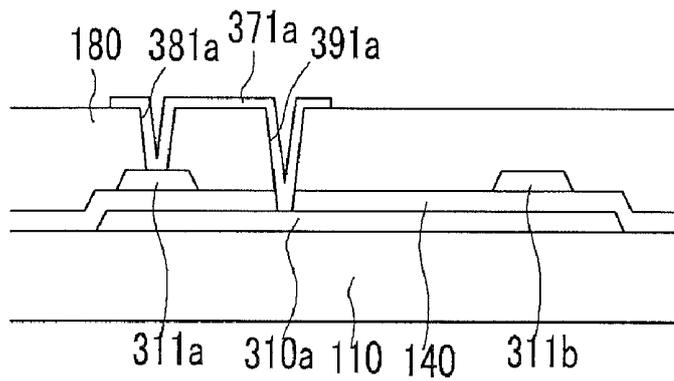


FIG. 21

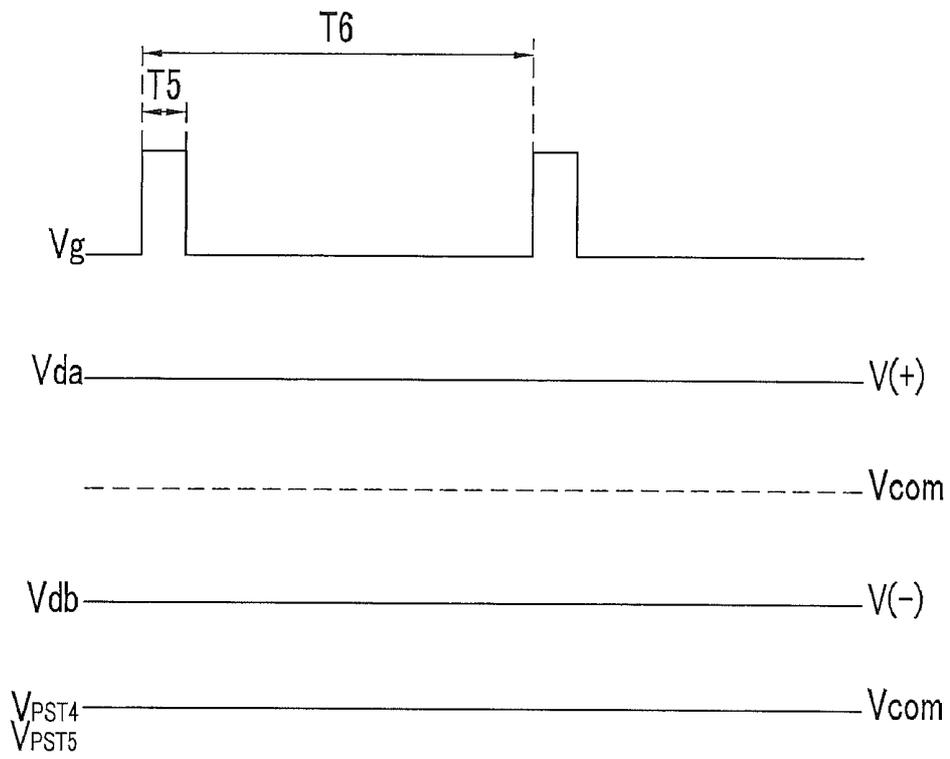
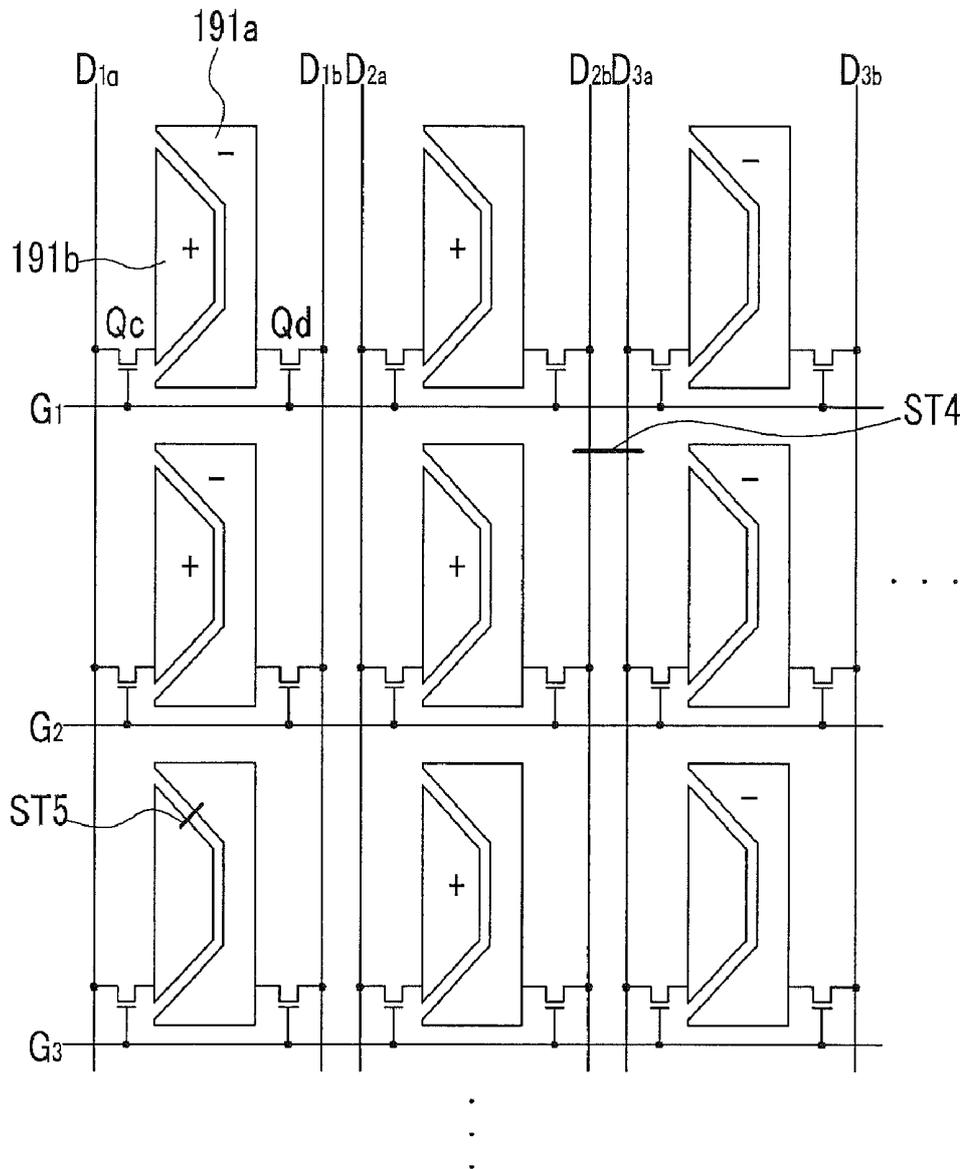


FIG. 22



LIQUID CRYSTAL DISPLAY AND TEST METHOD THEREOF

This application is a divisional application of U.S. application Ser. No. 11/359,955, filed on Feb. 22, 2006, which claims priority to Korean Patent Applications No. 2005-0014578, filed on Feb. 22, 2005 and No. 2005-0047262, filed on Jun. 2, 2005, and all the benefits accruing therefrom under 35 U.S.C. §119, and the contents of which in their entireties are herein incorporated by reference.

BACKGROUND OF THE INVENTION

(a) Field of the Invention

The present invention relates to a liquid crystal display, and a method of testing the liquid crystal display. More particularly, the present invention relates to a liquid crystal display and a method of testing the liquid crystal display which easily detects the formation of a bridge between sub-pixel electrodes as well as between data lines of the liquid crystal display.

(b) Description of the Related Art

A liquid crystal display ("LCD"), an extensively used flat panel display device, includes two display panels mounting field-generating electrodes such as pixel and common electrodes thereon, and a liquid crystal layer sandwiched between the electrodes. The LCD generates an electric field in the liquid crystal layer by applying voltages to the field-generating electrodes, and aligns the liquid crystal molecules within the liquid crystal layer to control the polarization of light incident thereto, thereby displaying desired images.

Various tests should be made to detect defects of line breaks or short-circuits in fabricating the LCD, such as an open short ("OS") test, an array test, a visual inspection ("VI") test, a gross test, and a module test.

When source and drain electrodes are separated from each other during the process of fabricating a thin film transistor ("TFT") on a first panel in the LCD, the OS test is made to detect a break of the signal lines or a short-circuit of the TFT by applying a predetermined voltage thereto. Before the mother glass is divided into a plurality of cells, the array test is made to detect a break of the display signal lines by applying a predetermined voltage thereto and identifying the presence or absence of the output voltage. After the mother glass is divided into the plurality of cells and the upper and lower panels are assembled with each other, the VI test is made to visually detect a break of the display signal lines by applying a predetermined voltage thereto. Before the driving circuit is mounted, the gross test is made to detect the display image quality and a break of the display signal lines by applying the same voltage as the practical driving voltage thereto and identifying the display screen state. After the driving circuit is mounted, the module test is made to finally detect the optimal operation of the driving circuit.

A vertically-aligned ("VA") mode LCD provides an LCD in which the directors of liquid crystal molecules are aligned vertical to the upper and lower panels with no application of an electric field, as this gives a high contrast ratio and a wide reference viewing angle. The reference viewing angle refers to a viewing angle with a contrast ratio of 1:10, or an inter-gray luminance inversion limit angle.

With the VA mode LCD, cutouts or protrusions may be formed on the field-generating electrodes to realize the wide viewing angle. As the direction of the liquid crystal molecules to be inclined is determined by way of the cutouts or protrusions,

the inclination directions of the liquid crystal molecules can be diversified, thereby widening the reference viewing angle.

However, the VA mode LCD involves poor visibility at the lateral side thereof, compared to the visibility at the front side thereof. For example, with the case of a patterned vertically aligned ("PVA") mode LCD having cutouts, the luminance thereof is heightened as it comes to the lateral side thereof, and in a serious case, the luminance difference between high grays is eradicated so that the display image may appear to be distorted.

In order to enhance the lateral side visibility, it has been proposed that each pixel should be divided into two sub-pixels, with the sub-pixels within each pixel receiving different voltages. However, when electrodes for the sub-pixels are patterned during the process of fabricating the LCD, a bridge may be formed such that it interconnects the sub-pixel electrodes or the neighboring data lines. From the circuit perspective, this means that those electrodes or data lines are short-circuited with each other. Consequently, the same voltage, rather than different voltages, is applied to the respective sub-pixels, thereby deteriorating the display image quality.

BRIEF SUMMARY OF THE INVENTION

When the electrodes or data lines are short-circuited by a connection, the bridge formation should be detected through making various kinds of tests. The present invention thus provides a liquid crystal display ("LCD") and a method of testing the LCD which easily detects the formation of a bridge between the sub-pixel electrodes as well as between the data lines.

An LCD with the following features is provided with a test method thereof.

According to exemplary embodiments of the present invention, an LCD includes a plurality of pixel electrodes arranged in a matrix, each pixel electrode having first and second sub-pixel electrodes differentiated in size from each other, and first and second switching elements connected to the first and second sub-pixel electrodes, respectively. First and second gate lines are connected to the first and second switching elements, respectively. A data line is connected to the first and second switching elements and transmits a data voltage. First and second gate shorting bars are connected to the first and second gate lines, respectively.

First and second gate test signals that are different from each other may be applied to the first and second gate shorting bars, respectively.

A positive data voltage may be applied to the data line under application of the first gate test signal, and a negative data voltage is applied to the data line under application of the second gate test signal.

The positive and negative data voltages may have a substantially same dimension.

A data shorting bar may be connected to the data line, and may be formed in a same layer of the LCD as the first and second gate lines.

A shielding electrode may be overlapped with the data line, and disposed between the two neighboring pixel electrodes.

The shielding electrode may be overlapped with at least one of the first and second gate lines.

The data voltages applied to the first and second sub-pixel electrodes may be differentiated in dimension from each other, and obtained from one image information set.

The first sub-pixel electrode may be larger in size than the second sub-pixel electrode, and the dimension of the data

voltage applied to the first sub-pixel electrode may be smaller than the dimension of the data voltage applied to the second sub-pixel electrode.

The first and second gate shorting bars may be formed in a same layer of the liquid crystal display as the data line, and may be substantially parallel to the data line.

The first and second gate shorting bars may fall outside a periphery of a display panel for the LCD.

The LCD may further include gate pads connected to the first and second gate lines, respectively, and gate extension lines connecting the gate pads to the first and second gate shorting bars, respectively.

According to other exemplary embodiments of the present invention, an LCD includes a plurality of pixel electrodes arranged in a matrix, each pixel electrode having first and second sub-pixel electrodes differentiated in size from each other, and first and second switching elements connected to the first and second sub-pixel electrodes, respectively. First and second gate lines are connected to the first and second switching elements, respectively. A data line is connected to the first and second switching elements and transmits a data voltage. First and second gate shorting bars are connected to the first and second gate lines at odd-numbered pixel rows. Third and fourth gate shorting bars are connected to the first and second gate lines at even-numbered pixel rows.

First to fourth gate test signals may be applied to the first to fourth gate shorting bars, respectively.

A positive data voltage may be applied to the data line under application of the first and fourth gate test signals, while a negative data voltage is applied to the data line under application of the second and third gate test signals.

According to other exemplary embodiments of the present invention, a method of testing an LCD including a plurality of pixel electrodes having first and second sub-pixel electrodes, first and second switching elements connected to the first and second sub-pixel electrodes, respectively, first and second gate lines connected to the first and second switching elements, respectively, and a data line connected to the first and second switching elements, includes providing first and second gate shorting bars connected to the first and second gate lines, respectively, providing a data shorting bar connected to the data line, applying a positive data voltage to the data shorting bar, applying a first gate test signal to the first gate shorting bar to apply the positive data voltage to the first sub-pixel electrode, applying a negative data voltage to the data shorting bar, and applying a second gate test signal to the second gate shorting bar to apply the negative data voltage to the second sub-pixel electrode.

The method may further include detecting polarities of the first and second sub-pixel electrodes, such as by performing an array test.

The method may further include identifying existence of a bridge between the first and second sub-pixel electrodes, wherein positive and negative pixel voltages of the first and second sub-pixel electrodes having a bridge are not continuously sustained under application of positive and negative data voltages.

The method may further include detecting uniformity in luminance of the LCD, such as by performing a visual inspection test.

The method may further include identifying existence of a bridge between the first and second sub-pixel electrodes when brightness of a pixel having the first and second sub-pixel electrodes with a bridge is differentiated in brightness from other pixels not having a bridge.

The method may further include identifying existence of a bridge between the first sub-pixel electrode and a shielding electrode.

The method may further include separating the first and second gate shorting bars from the first and second gate lines, and separating the data shorting bar from the data line.

According to other exemplary embodiments of the present invention, a method of testing an LCD including a plurality of pixel electrodes having first and second sub-pixel electrodes, first and second switching elements connected to the first and second sub-pixel electrodes, respectively, first and second gate lines connected to the first and second switching elements, respectively, and a data line connected to the first and second switching elements, includes providing first and second gate shorting bars connected to the first and second gate lines at odd-numbered pixel rows, respectively, providing third and fourth gate shorting bars connected to the first and second gate lines at even-numbered pixel rows, respectively, providing a data shorting bar connected to the data line, applying a positive data voltage to the data shorting bar, applying a first gate test signal to the first gate shorting bar to apply the positive data voltage to the first sub-pixel electrode at the odd-numbered pixel rows, applying a negative data voltage to the data shorting bar, applying second and third gate test signals to the second and third gate shorting bars to apply the negative data voltage to the second sub-pixel electrode at the odd-numbered pixel rows and to the first sub-pixel electrode at the even-numbered pixel rows, and applying a fourth gate test signal to the fourth gate shorting bar to apply the positive data voltage to the second sub-pixel electrode at the even-numbered pixel rows.

The method may further include detecting polarities of the first and second sub-pixel electrodes.

The method may further include identifying existence of a bridge between the first and second sub-pixel electrodes.

The method may further include identifying existence of a bridge between the first sub-pixel electrodes of adjacent pixels.

The positive and negative data voltages may have substantially same dimensions.

The method may further include detecting uniformity of luminance of the LCD.

The method may further include separating the first and second gate shorting bars from the first and second gate lines at the odd-numbered pixel rows, separating the third and fourth gate shorting bars from the first and second gate lines at the even-numbered pixel rows, and separating the data shorting bar from the data line.

According to other exemplary embodiments of the present invention, an LCD includes a plurality of pixel electrodes arranged in a matrix, each pixel electrode having first and second sub-pixel electrodes differentiated in size from each other, and first and second switching elements connected to the first and second sub-pixel electrodes, respectively. A gate line is connected to the first and second switching elements. First and second data lines cross the gate line, and are connected to the first and second switching elements, respectively. First and second data shorting bars are connected to the first and second data lines, respectively.

Data voltages differentiated in polarity from each other may be applied to the first and second data shorting bars.

The data voltages differentiated in polarity from each other may have substantially same dimension.

A gate shorting bar may be connected to the gate line.

Data voltages applied to the first and second sub-pixel electrodes may be differentiated in dimension from each other, and are obtained from one image information set.

The first sub-pixel electrode may be larger in size than the second sub-pixel electrode, and dimension of the data voltage applied to the first sub-pixel electrode is smaller than dimension of the data voltage applied to the second sub-pixel electrode.

The first and second data shorting bars may be formed in a same layer of the liquid crystal display as the gate line.

The first and second data shorting bars may be substantially parallel to the gate line.

The first and second data shorting bars may fall outside a periphery of a display panel for the LCD.

According to other exemplary embodiments of the present invention, a method of testing a liquid crystal display including a plurality of pixel electrodes having first and second sub-pixel electrodes, first and second switching elements connected to the first and second sub-pixel electrodes, respectively, a gate line connected to the first and second switching elements, and first and second data lines connected to the first and second switching elements, respectively, includes providing first and second data shorting bars connected to the first and second data lines, providing a gate shorting bar connected to the gate line, applying a positive data voltage to the first data shorting bar, applying a negative data voltage to the second data shorting bar, and applying a gate test signal to the gate shorting bar to apply the positive data voltage to the first sub-pixel electrode and to apply the negative data voltage to the second sub-pixel electrode.

The method includes detecting uniformity of luminance of the LCD.

The method may further include identifying existence of a bridge between the first and second data lines.

The method may further include identifying existence of a bridge between the first and second sub-pixel electrodes.

The positive and negative data voltages have substantially same dimension.

The method may further include separating the first and second data shorting bars from the first and second data lines, and separating the gate shorting bar from the gate line.

BRIEF DESCRIPTION OF THE DRAWINGS

The present invention will become more apparent by describing embodiments thereof in detail with reference to the accompanying drawings, in which:

FIG. 1 is a schematic view of an exemplary embodiment of an LCD according to the present invention;

FIG. 2 is an equivalent circuit diagram of an exemplary pixel of an exemplary embodiment of an LCD according to the present invention;

FIG. 3 is an equivalent circuit diagram of an exemplary sub-pixel of an exemplary embodiment of an LCD according to the present invention;

FIG. 4 is a plan view of an exemplary embodiment of an LCD according to the present invention;

FIGS. 5 and 6 are cross-sectional views of the exemplary embodiment of the LCD taken along line V-V' and line VI-VI' of FIG. 4;

FIG. 7 is an amplified view of exemplary gate shorting bars of the exemplary embodiment of the LCD shown in FIG. 1;

FIG. 8 is a cross-sectional view of the exemplary embodiment of the LCD taken along line VIII-VIII' of FIG. 7;

FIG. 9 is a test waveform diagram for an exemplary embodiment of an LCD according to the present invention;

FIG. 10 illustrates the polarities of exemplary pixels of an exemplary embodiment of an LCD according to the present invention;

FIG. 11 is a schematic view of another exemplary embodiment of an LCD according to the present invention;

FIG. 12 is an amplified view of exemplary gate shorting bars of the exemplary embodiment of the LCD shown in FIG. 11;

FIG. 13 is a test waveform diagram for another exemplary embodiment of an LCD according to the present invention;

FIG. 14 illustrates the polarities of pixels of another exemplary embodiment of an LCD according to the present invention;

FIG. 15 is a schematic view of another exemplary embodiment of an LCD according to the present invention;

FIG. 16 is an equivalent circuit diagram of an exemplary pixel of another exemplary embodiment of an LCD according to the present invention;

FIG. 17 is a plan view of another exemplary embodiment of an LCD according to the present invention;

FIG. 18 is a cross sectional view of the exemplary embodiment of the LCD taken along line XVIII-XVIII' of FIG. 17;

FIG. 19 is an amplified view of exemplary data shorting bars of the exemplary embodiment of the LCD shown in FIG. 15;

FIG. 20 is a cross-sectional view of the exemplary embodiment of the LCD taken along line XX-XX' of FIG. 19;

FIG. 21 is a test waveform diagram for another exemplary embodiment of an LCD according to the present invention; and

FIG. 22 illustrates the polarities of exemplary pixels of another exemplary embodiment of an LCD according to the present invention.

DETAILED DESCRIPTION OF THE INVENTION

The invention will now be described more fully hereinafter with reference to the accompanying drawings, in which embodiments of the invention are shown. This invention may, however, be embodied in many different forms and should not be construed as limited to the embodiments set forth herein. Rather, these embodiments are provided so that this disclosure will be thorough and complete, and will fully convey the scope of the invention to those skilled in the art. Like reference numerals refer to like elements throughout. In the drawings, the thickness of layers, films, and regions are exaggerated for clarity.

It will be understood that when an element is referred to as being "on" another element, it can be directly on the other element or intervening elements may be present there between. In contrast, when an element is referred to as being "directly on" another element, there are no intervening elements present. As used herein, the term "and/or" includes any and all combinations of one or more of the associated listed items.

It will be understood that, although the terms first, second, third etc. may be used herein to describe various elements, components, regions, layers and/or sections, these elements, components, regions, layers and/or sections should not be limited by these terms. These terms are only used to distinguish one element, component, region, layer or section from another element, component, region, layer or section. Thus, a first element, component, region, layer or section discussed below could be termed a second element, component, region, layer or section without departing from the teachings of the present invention.

The terminology used herein is for the purpose of describing particular embodiments only and is not intended to be limiting of the invention. As used herein, the singular forms "a", "an" and "the" are intended to include the plural forms as

well, unless the context clearly indicates otherwise. It will be further understood that the terms “comprises” and/or “comprising,” or “includes” and/or “including” when used in this specification, specify the presence of stated features, regions, integers, steps, operations, elements, and/or components, but do not preclude the presence or addition of one or more other features, regions, integers, steps, operations, elements, components, and/or groups thereof.

Spatially relative terms, such as “beneath”, “below”, “lower”, “above”, “upper” and the like, may be used herein for ease of description to describe one element or feature’s relationship to another element(s) or feature(s) as illustrated in the figures. It will be understood that the spatially relative terms are intended to encompass different orientations of the device in use or operation in addition to the orientation depicted in the figures. For example, if the device in the figures is turned over, elements described as “below” or “beneath” other elements or features would then be oriented “above” the other elements or features. Thus, the exemplary term “below” can encompass both an orientation of above and below. The device may be otherwise oriented (rotated 90 degrees or at other orientations) and the spatially relative descriptors used herein interpreted accordingly.

Unless otherwise defined, all terms (including technical and scientific terms) used herein have the same meaning as commonly understood by one of ordinary skill in the art to which this invention belongs. It will be further understood that terms, such as those defined in commonly used dictionaries, should be interpreted as having a meaning that is consistent with their meaning in the context of the relevant art and the present disclosure, and will not be interpreted in an idealized or overly formal sense unless expressly so defined herein.

Embodiments of the present invention are described herein with reference to cross section illustrations that are schematic illustrations of idealized embodiments of the present invention. As such, variations from the shapes of the illustrations as a result, for example, of manufacturing techniques and/or tolerances, are to be expected. Thus, embodiments of the present invention should not be construed as limited to the particular shapes of regions illustrated herein but are to include deviations in shapes that result, for example, from manufacturing. For example, a region illustrated or described as flat may, typically, have rough and/or nonlinear features. Moreover, sharp angles that are illustrated may be rounded. Thus, the regions illustrated in the figures are schematic in nature and their shapes are not intended to illustrate the precise shape of a region and are not intended to limit the scope of the present invention.

Now, exemplary embodiments of LCDs and test methods thereof according to the present invention will be described with reference to the accompanying drawings.

FIG. 1 is a schematic view of an exemplary embodiment of an LCD according to the present invention, FIG. 2 is an equivalent circuit diagram of an exemplary pixel of an exemplary embodiment of an LCD according to the present invention, and FIG. 3 is an equivalent circuit diagram of an exemplary sub-pixel of an exemplary embodiment of an LCD according to the present invention.

As shown in FIG. 1, an exemplary embodiment of an LCD includes a liquid crystal panel assembly, which has, from the equivalent circuit perspective, a plurality of display signal lines $G1a$ - Gnb and $D1$ - Dm , and a plurality of pixels PX connected to the display signal lines $G1a$ - Gnb and $D1$ - Dm and arranged roughly in the form of a matrix. With the structure shown in FIG. 3, the liquid crystal panel assembly includes lower and upper panels **100** and **200**, and a liquid

crystal layer **3** disposed between the two panels **100** and **200**. The lower panel **100** may also be known as a thin film transistor (“TFT”) panel or first panel, and the upper panel **200** may also be known as a common electrode panel, a color filter panel, or a second panel.

The display signal lines $G1a$ - Gnb and $D1$ - Dm are provided at the lower panel **100** with a plurality of gate lines $G1a$ - Gnb for transmitting gate signals (also called the “scanning signals”) and data lines $D1$ - Dm for transmitting data signals. The gate lines $G1a$ - Gnb extend in the direction of pixel rows substantially parallel to each other in a first direction, and the data lines $D1$ - Dm extend in the direction of pixel columns substantially parallel to each other in a second direction. The first direction may be substantially perpendicular to the second direction.

The liquid crystal panel assembly further includes gate pads $PG1a$ - $PGnb$ connected to the gate lines $G1a$ - Gnb , respectively, and data pads $PD1$ - PDm connected to the data lines $D1$ - Dm , respectively. That is, each gate line $G1a$ - Gnb is connected to one gate pad PG , and each data line $D1$ - Dm is connected to one data pad PD . First and second gate shorting bars **320a** and **320b** are connected to the relevant gate pads $PG1$ - $PGnb$, and a data shorting bar **310** is connected to the respective data pads $PD1$ - PDm .

The first gate shorting bar **320a** is connected to the first gate pads $PG1a$, $PG2a$, $PG3a$, . . . via first gate extension lines **321a**, **322a**, **323a**, . . . , and the second gate shorting bar **320b** is connected to the second gate pads $PG1b$, $PG2b$, . . . via second gate extension lines **321b**, **322b**, The first and second gate shorting bars **320a** and **320b** may extend substantially perpendicular to the gate lines $G1a$ - Gnb , and substantially parallel to the data lines $D1$ - Dm . The data shorting bar **310** is connected to the data pads $PD1$, $PD2$, $PD3$, . . . via data extension lines **311**, **312**, **313**, The data shorting bar **310** may extend substantially perpendicular to the data lines $D1$ - Dm , and substantially parallel to the gate lines $G1a$ - Gnb . Accordingly, the respective first gate lines $G1a$ - Gna are connected to each other via the first gate shorting bar **320a**, and the respective second gate lines $G1b$ - Gnb are connected to each other via the second gate shorting bar **320b**. Furthermore, the respective data lines $D1$ - Dm are connected to each other via the data shorting bar **310**.

Separate pads (not shown) are provided at the ends of the gate shorting bars **320a** and **320b** and the data shorting bar **310** to apply various kinds of test signals, as will be further described below.

The gate shorting bars **320a** and **320b** and the data shorting bar **310** undergo several tests, and are then removed along the LX line thereof. That is, elements within an interior of the LX periphery are retained for the LCD, and elements outside of the LX periphery, such as the first and second gate shorting bars **320a**, **320b** and the data shorting bar **310**, are removed. Consequently, by removal of the shorting bars **320a**, **320b**, and **310**, the respective gate and data lines $G1a$ - Gnb and $D1$ - Dm are separated from each other. A gate driver (not shown) and a data driver (not shown) are externally connected to the gate and the data pads $PG1a$ - $PGnb$ and $PD1$ - PDm to apply gate and data signals to the gate and the data lines $G1a$ - Gnb and $D1$ - Dm , respectively. However, in the case that the gate driver is integrated at the liquid crystal panel assembly, the gate pads may be omitted while extending the gate extension lines **321a**, **321b**, **322a**, **322b**, . . . from the gate driver.

FIG. 2 illustrates the display signal lines and an equivalent circuit at an exemplary pixel Px , in which the display signal lines include gate lines indicated by GLa and GLb , a data line

indicated by DL, and a storage electrode line SL extending nearly parallel to the gate lines GLa and GLb and dissecting the pixel PX.

The respective pixels Px include a pair of sub-pixels Pxa and Pxb, each of which has switching elements Qa and Qb connected to the relevant gate lines GLa and GLb and the data line DL, liquid crystal capacitors C_{LCa} and C_{LCb} connected to the switching elements Qa and Qb, and storage capacitors C_{STa} and C_{STb} connected to the switching elements Qa and Qb and the storage electrode line SL. In an alternative embodiment, the storage capacitors C_{STa} and C_{STb} may be omitted, and in such a case, the storage electrode line SL is dispensed with.

As shown in FIGS. 1 and 2, all the first gate lines GLa are connected to the first gate shorting bar 320a, and all the second gate lines GLb are connected to the second gate shorting bar 320b. Consequently, the same signal may be applied to the respective first sub-pixels Pxa, and the same signal may be applied to the respective second sub-pixels Pxb, however the signal applied to the first sub-pixels Pxa may be different from the signal applied to the second sub-pixels Pxb, as will be further described below.

As shown in FIG. 3, the switching element Q at the respective sub-pixels Pxa and Pxb is formed with a TFT formed at the lower panel 100, which is a triode device with a control terminal (gate) connected to the gate line GL, an input terminal (source) connected to the data line DL, and an output terminal (drain) connected to the liquid crystal capacitor C_{LC} and the storage capacitor C_{ST} . While only one sub-pixel Pxb is illustrated in FIG. 3, it should be understood that each pixel PX also includes sub-pixel Pxa, as previously illustrated in FIG. 2.

The liquid crystal capacitor C_{LC} employs the sub-pixel electrode PE of the lower panel 100 and the common electrode CE of the upper panel 200 as two terminals. The liquid crystal layer 3 disposed between the two electrodes PE and CE functions as a dielectric. The sub-pixel electrode PE is connected to the switching element Q, and the common electrode CE is formed on the entire surface, or at least substantially the entire surface, of the upper panel 200 to receive a common voltage Vcom. Alternatively, the common electrode CE may be provided at the lower panel 100, and in this case, at least one of the two electrodes PE and CE is formed in the shape of a line or a bar.

With the storage capacitor C_{ST} subsidiary to the liquid crystal capacitor C_{LC} , the storage electrode line SL and the pixel electrode PE provided at the lower panel 100 are overlapped with each other while interposing an insulator, and a predetermined voltage such as a common voltage Vcom is applied to the storage electrode line SL. Alternatively, the storage capacitor C_{ST} may be formed by overlapping the sub-pixel electrode PE with the immediate previous gate line while interposing an insulator.

In order for the liquid crystal panel assembly to display colors, the respective pixels may intrinsically express one of the primary (main) colors (the spatial division), or alternately express the primary colors in temporal order (the time division) such that the desired colors can be perceived by the spatial and temporal sum of the primary colors. The primary colors preferably include red, green, and blue colors, however alternate colors are also within the scope of these embodiments. FIG. 3 shows an example of the time division where each pixel has a color filter CF expressing one of the primary colors at the region of the upper panel 200. In an alternative embodiment, the color filter CF may be formed over or under the sub-pixel electrode PE of the lower panel 100.

The structure of the LCD will be further described with reference to FIGS. 4 to 6.

FIG. 4 is a plan view of an exemplary embodiment of an LCD according to the present invention, and FIGS. 5 and 6 are cross-sectional views of the exemplary embodiment of the LCD taken along line V-V' and line VI-VI' of FIG. 4.

The LCD as illustrated in FIGS. 4-6 includes a lower panel 100, an upper panel 200 facing the lower panel 100, and a liquid crystal layer 3 disposed between the panels 100 and 200.

First, the lower panel 100 will be further described.

An insulating substrate 110 based on transparent glass or plastic is overlaid with pairs of first and second gate lines 121a and 121b, and a plurality of storage electrode lines 131.

The gate lines 121a and 121b extend horizontally such as in a transverse or first direction, and are physico-electrically separated from each other to transmit gate signals. The first and second gate lines 121a and 121b include portions that deviate from the longitudinal direction of the first and second gate lines 121a and 121b, and have left-sided wide area end portions 129a and 129b for connecting a plurality of first and second gate electrodes 124a and 124b, protruded from the first and second gate lines 121a and 121b, to another layer or an external driving circuit. Alternatively, the end portions 129a and 129b may be arranged at the left and right sides, such as alternately arranged, or both only at the right side.

The storage electrode line 131 also extends horizontally, substantially parallel to the first and second gate lines 121a and 121b, and may be located closer to the first gate line 121a than to the second gate line 121b. The respective storage electrode lines 131 include a plurality of storage electrodes 137 protruding from the storage electrode line 131 with a wide area. The storage electrodes 137 may be rectangular shaped and symmetrical to the storage electrode line 131. A predetermined voltage is applied to the storage electrode lines 131, such as a common voltage applied to a common electrode 270 of the upper panel 200 of the LCD.

The gate lines 121a and 121b and the storage electrode line 131 are formed with an aluminum-based metallic material such as aluminum (Al) and an aluminum alloy, a silver-based metallic material such as silver (Ag) and a silver alloy, a copper-based metallic material such as copper (Cu) and a copper alloy, a molybdenum-based metallic material such as molybdenum (Mo) and a molybdenum alloy, chromium (Cr), titanium (Ti), or tantalum (Ta). Alternatively, the gate lines 121a and 121b and the storage electrode line 131 may have a multi-layered structure with two conductive layers (not shown) differentiated in physical properties thereof. If a multi-layered structure is employed, one of the conductive layers may be formed with a metallic material having low resistivity such as an aluminum-based metallic material, a silver-based metallic material, and a copper-based metallic material such that it can reduce the signal delay or voltage drop of the gate lines 121a and 121b and the storage electrode line 131. By contrast, the other conductive layer in a multi-layered structure may be formed with a material having an excellent contact characteristic with respect to other materials such as indium tin oxide ("ITO") and indium zinc oxide ("IZO"), such as a molybdenum-based metallic material, chromium, titanium, and tantalum. Examples of such a combination include a structure with a chromium-based lower layer and an aluminum-based upper layer, and a structure with an aluminum-based lower layer and a molybdenum-based upper layer. While particular embodiments and examples have been described, the gate lines 121a and 121b and the storage electrode line 131 may be formed with various kinds of other metallic materials and conductors.

The lateral sides of the gate lines **121a** and **121b** and the storage electrode line **131** are inclined with respect to the surface of the insulating substrate **110**, and the inclination angle thereof preferably ranges between about 30 to about -80° .

A gate insulating layer **140** is formed on the gate lines **121a** and **121b** and the storage electrode line **131** and may be further formed over exposed portions of the insulating substrate **110**. The gate insulating layer **140** may be made with silicon nitride (SiNx) or the like.

A plurality of island-shaped semiconductors **154a**, **154b** and **156** are formed on the gate insulating layer **140** with hydrogenated amorphous silicon ("a-Si"). The semiconductors **154a** and **154b** are formed on the gate electrodes **124a** and **124b**, respectively. The semiconductor **156** is formed on the gate lines **121a** and **121b** and the storage electrode line **131**.

A plurality of island-shaped ohmic contacts **163a**, **165a** and **166** are formed on the semiconductors **154a**, **154b**, and **156** with n+ hydrogenated a-Si where n-type impurities such as silicide and phosphorous are doped at a high concentration. A pair of the first ohmic contacts **163a** and **165a** and a pair of the second ohmic contact (not illustrated) are placed on the semiconductors **154a** and **154b**, respectively and are spaced apart from each other to form a channel on the semiconductors **154a** and **154b**.

The lateral sides of the semiconductors **154a**, **154b**, and **156** and the ohmic contacts **163a**, **165a**, and **166** are inclined with respect to the surface of the insulating substrate **110**, and the inclination angles thereof are preferably in a range of about 30 to about 80° .

A plurality of data lines **171** and pairs of drain electrodes **175a** and **175b** separated from the data lines **171** are formed on the ohmic contacts **163a**, **165a**, and **166**, and on the gate insulating layer **140**.

The data lines **171** extend vertically, such as in a longitudinal or second direction, such that they cross the gate lines **121a** and **121b** and the storage electrode line **131** to transmit data voltages thereto. The data lines **171** are insulated from the gate lines **121a** and **121b** by the gate insulating layer **140** disposed there between. The respective data lines **171** include a plurality of first and second source electrodes **173a** and **173b** extended toward the first and second drain electrodes **175a** and **175b**, respectively, and end portions **179** enlarged in width to make a connection with another layer or an external device, such as a data driving circuit.

The first and second drain electrodes **175a** and **175b** extend in first and second directions from the bar-shaped end portions thereof placed over the semiconductors **154a** and **154b**, towards the storage electrode **137**, and have wide extensions **177a** and **177b** overlapped with the storage electrode **137**. The respective source electrodes **173a** and **173b** are bent such that they surround the bar-shaped end portions of the drain electrodes **175a** and **175b**. The first and second gate electrodes **124a** and **124b**, the first and second source electrodes **173a** and **173b**, and the first and second drain electrodes **175a** and **175b** form first and second thin film transistors ("TFTs") Qa and Qb together with the semiconductors **154a** and **154b**. The channels of the TFTs Qa and Qb are formed on the semiconductors **154a** and **154b** between the first and second source electrodes **173a** and **173b** and the first and second drain electrodes **175a** and **175b** and between the island-shaped ohmic contacts **163a**, **165a**.

The data line **171** and the drain electrodes **175a** and **175b** are preferably formed with a chromium-based metallic metal, a molybdenum-based metal, or a refractory metallic material such as tantalum and titanium, and may have a multi-layered

structure with a lower layer (not shown) based on the refractory metal, and an upper layer (not shown) formed on the lower layer with a low resistance material. Examples of the multi-layered structure include, but are not limited to, a triple-layered structure with a molybdenum layer—an aluminum layer—a molybdenum layer in addition to the double-layered structure with a chromium or molybdenum-based lower layer and an aluminum-based upper layer. However, the data lines **171** and the drain electrodes **175a** and **175b** may be made of various metals or conductors.

As with the gate lines **121a** and **121b** and the storage electrode line **131**, the lateral sides of the data line **171** and the drain electrodes **175a** and **175b** have inclined edge profiles with respect to a surface of the insulating substrate **110**, and the inclination angles thereof range about 30 to about 80° .

The ohmic contacts **163a**, **163b**, **165a**, **165b**, and **166** are only interposed between the underlying semiconductors **154a**, **154b**, and **156** and the overlying data line **171** and drain electrodes **175a** and **175b** to lower the contact resistance therebetween. The semiconductors **154a** and **154b** have portions exposed through the source electrodes **173a** and **173b** and the drain electrodes **175a** and **175b**. Furthermore, as described above, the semiconductors **156** are formed at the crossed regions of the gate lines **121a** and **121b** and the storage electrode and data lines **131** and **171** and at the crossed regions of the drain electrodes **175a** and **175b** and the storage electrode **137** to smooth the profile thereof at those crossed regions and prevent the data line **171** and the drain electrodes **175a** and **175b** from being cut.

A passivation layer **180** is formed on the data line **171**, the drain electrodes **175a** and **175b**, and the exposed portions of the semiconductors **154a** and **154b**. The passivation layer **180** may be further formed on exposed portions of the gate insulating layer **140** as shown. The passivation layer **180** is formed with an inorganic material based on silicon nitride or silicon oxide, an organic material bearing excellent flattening characteristics and photosensitivity, or a low dielectric insulating material such as a-Si:C:O and a-Si:O:F formed through plasma enhanced chemical vapor deposition ("PECVD"). Alternatively, the passivation layer **180** may have a double-layered structure with a lower inorganic layer and an upper inorganic layer to protect the exposed portions of the semiconductors **154a** and **154b** while ensuring the excellent characteristics of the organic layer.

A plurality of contact holes **182**, **187a**, and **187b** are formed at the passivation layer **180** to expose the end portions **179** of the data line **171** and the extensions **177a** and **177b** of the drain electrodes **175a** and **175b**. A plurality of contact holes **181a** and **181b** are formed at the passivation layer **180** and the gate insulating layer **140** to expose the end portions **129a** and **129b** of the gate lines **121a** and **121b**.

A plurality of pixel electrodes **190** with first and second sub-pixel electrodes **190a** and **190b**, a plurality of shielding electrodes **88**, and a plurality of contact assistants **81a**, **81b**, and **82** are formed on the passivation layer **180**. The pixel electrodes **190**, the shielding electrodes **88**, and the contact assistants **81a**, **81b**, and **82** are formed with a transparent conductive material such as ITO and IZO, or a reflective conductive material such as aluminum for use in a reflective LCD.

The first and second sub-pixel electrodes **190a** and **190b** are physico-electrically connected to the first and second drain electrodes **175a** and **175b** through the contact holes **187a** and **187b** to receive data voltages from the first and second drain electrodes **175a** and **175b**. Predetermined voltages different from each other are applied to a pair of the sub-pixel electrodes **190a** and **190b** with respect to one input

image signal, and the dimensions thereof are determined depending upon the dimension and shape of the sub-pixel electrodes **190a** and **190b**. Furthermore, the areas of the sub-pixel electrodes **190a** and **190b** may differ from each other. For instance, the second sub-pixel electrode **190b** receives a voltage higher than that of the first sub-pixel electrode **190a**, and has an area smaller than that of the first sub-pixel electrode **190a**.

Upon receipt of the data voltages, the sub-pixel electrodes **190a** and **190b** generate electric fields together with the common electrode **270** of the opposing panel **200** supplied with a common voltage, and align the liquid crystal molecules of the liquid crystal layer **3** between the two electrodes **190a** and **190b** and the common electrode **270**.

As described above, the sub-pixel electrodes **190a** and **190b** and the common electrode **270** form liquid crystal capacitors C_{LCa} and C_{LCb} to sustain the voltages applied thereto even after the TFTs **Qa** and **Qb** turn off. Storage capacitors C_{STa} and C_{STb} are arranged parallel to the liquid crystal capacitors C_{LCa} and C_{LCb} to reinforce the voltage storage capacity. The storage capacitors C_{STa} and C_{STb} are formed by overlapping the first and second sub-pixel electrodes **190a** and **190b** with the drain electrodes **175a** and **175b** and the storage electrodes **137** connected thereto.

The respective pixel electrodes **190** are chamfered or edge-cut at the right corner thereof, and the cut leg is angled against the gate lines **121a** and **121b** at about 45°.

A pair of the first and second sub-pixel electrodes **190a** and **190b** forming one pixel electrode **190** engage with each other while interposing a gap **94**, and the pixel electrode **190** is outlined roughly with a rectangular shape. The second sub-pixel electrode **190b** is shaped as a rotated equilateral trapezoid having a trapezoid-hollowed base. The second sub-pixel electrode **190b** is mostly surrounded by the first sub-pixel electrode **190a**, that is, the second sub-pixel electrode **190b** is nested within the first sub-pixel electrode **190a**. The first sub-pixel electrode **190a** is formed with an upper trapezoid, a lower trapezoid, and a middle trapezoid connected to each other at the left sides thereof. The first sub-pixel electrode **190a** has a pair of cutouts **91a** and **91b** extended from the top side of the upper trapezoid and the bottom side of the lower trapezoid to the right sides thereof. The cutout **91a** is formed with two cut sub-portions separated from each other at the meeting area thereof with the first gate line **121a**. The middle trapezoid of the first sub-pixel electrode **190a** is fitted into the hollowed base of the second sub-pixel electrode **190b**. The first sub-pixel electrode **190a** has a cutout **92** extended along the storage electrode line **131**, and the cutout **92** has an entrance at the left side of the first sub-pixel electrode **190a** adjacent the data line **171** for the pixel, and a horizontal portion horizontally extended from the entrance. The entrance of the cutout **92** has a pair of legs angled against the storage electrode line **131** at about 45°. The gap **94** between the first and second sub-pixel electrodes **190a** and **190b** has two pairs of upper and lower inclined portions angled against the gate lines **121a** and **121b** at about 45° substantially with a uniform width, and three vertical portions substantially with a uniform width. For explanatory convenience, the gap **94** may also be referred to as a cutout.

The pixel electrode **190** has cutouts **91a**, **91b**, and **92**, and is partitioned into a plurality of regions by way of the cutouts **91a**, **91b**, and **92** and the gap **94**. The cutouts **91a**, **91b**, and **92** obliquely extend from the left side of the pixel electrode **190** to the right side thereof, and are in inversion symmetry with the storage electrode line **131**. The cutouts are angled against the gate lines **121a** and **121b** at about 45°. The cutout **91a** and slanted portion of the gap **94** disposed on the upper half

portion of the pixel electrode **190** is substantially perpendicular to the cutout **91b** and slanted portion of the gap **94** disposed on the lower half portion of the pixel electrode **190**.

Accordingly, the upper half and the lower half of the pixel electrode **190** are divided into four regions by way of the cutouts **91a**, **91b**, and **92** and the gap **94**, respectively. While a particular arrangement has been illustrated and described, the number of division regions or cutouts may be varied depending upon the design factors such as pixel size, the length ratio of the horizontal to the vertical sides of the pixel electrode **190**, and the kinds or characteristics of the liquid crystal layer **3**.

The pixel electrode **190** is overlapped with the gate line **121** neighboring thereto to enhance the aperture ratio.

The shielding electrode **88** extends along the data line **171** and the gate line **121b**, and a portion thereof placed over the data line **171** completely covers the data line **171**. The portion of the shielding electrode **88** placed over the gate line **121b** is located within the boundary of the gate line **121b** with a width smaller than that of the gate line **121b**. The data line **171** disposed between the two neighboring pixel electrodes **190** is completely covered by the shielding electrode **88**. However, the width of the shielding electrode **88** may be controlled such that it is smaller than the data line **171**, or to have a boundary located external to the boundary of the gate line **121b**. A common voltage is applied to the shielding electrode **88**. For this purpose, the shielding electrode **88** is connected to the storage electrode line **131** through contact holes (not shown) within the passivation layer **180** and the gate insulating layer **140**, or to a short point (not shown) at which the common voltage is applied from the lower panel **100** to the upper panel **200**. It is preferable in minimizing the aperture ratio to reduce the distance between the shielding electrode **88** and the pixel electrode **190** as much as possible.

When the shielding electrode **88** receiving the common voltage is located over the data line **171**, the shielding electrode **88** shields an electric field formed between the data line **171** and the pixel electrode **190** as well as between the data line **171** and the common electrode **270**, thereby reducing voltage distortion of the pixel electrode **190** and signal delay and distortion of the data voltage transmitted by the data line **171**.

Furthermore, the pixel electrode **190** and the shielding electrode **88** should be spaced apart from each other with a sufficient distance to prevent short-circuiting thereof. Therefore, the pixel electrode **190** extends far enough from the data line **171** so that the parasitic capacitance therebetween is reduced. Moreover, as the permittivity of the liquid crystal layer **3** is higher than that of the passivation layer **180**, the parasitic capacitance between the data line **171** and the shielding electrode **88** is smaller than the parasitic capacitance between the data line **171** and the common electrode **270** in the absence of the shielding electrode **88**.

As the pixel electrode **190** and the shielding electrode **88** are formed with the same layer, the distance therebetween is uniformly maintained, and accordingly, the parasitic capacitance therebetween is sustained to be constant.

The contact assistants **81a**, **81b**, and **82** are connected to the end portions **129a** and **129b** of the gate lines **121a** and **121b** and the end portion **179** of the data line **171** through the contact holes **181a**, **181b**, and **182**, respectively. The contact assistants **81a**, **81b**, and **82** serve to reinforce the adhesion between the exposed end portions **129a** and **129b** of the gate lines **121a** and **121b** and the exposed end portion **179** of the data line **171** and external devices, and protect them.

An alignment layer **11** is formed on the pixel electrode **190**, the shielding electrode **88**, the contact assistants **81a**, **81b**, and

82, and the passivation layer 180, to align the liquid crystal layer 3. The alignment layer 11 may be a horizontally aligned layer.

A common electrode panel 200 will now be described.

A light blocking member 220, also termed a black matrix, is formed on an insulating substrate 210 based on transparent glass or plastic to prevent leakage of light. The light blocking member 220 faces the pixel electrode 190, and has a plurality of opening portions with the same shape as the pixel electrode 190. Alternatively, the light blocking member 220 may be formed with a portion corresponding to the data line 171, and portions corresponding to the TFTs Qa and Qb. However, the light blocking member 220 may be formed with various shapes to prevent the leakage of light around the pixel electrode 190 and the TFTs Qa and Qb.

A plurality of color filters 230 are formed on the substrate 210. The color filters 230 are mostly placed within the region surrounded by the light blocking member 220, and vertically and horizontally extend with respect to the pixel electrodes 190. The color filters 230 may express one of the three colors of red, green, and blue, although other colors are within the scope of these embodiments.

A cover layer or overcoat 250 is formed on the color filters 230 and the light blocking member 220 to prevent the color filters 230 from being exposed, and to provide a flattened surface. The cover layer 250 may be made of an organic insulator.

A common electrode 270 is formed on the cover layer 250 with a transparent conductive material such as, but not limited to, ITO and IZO.

The common electrode 270 has a plurality of sets of cutouts 271-274b.

Each set of the cutouts 271-274b faces one pixel electrode 190, and includes middle cutouts 271 and 272, upper cutouts 273a and 274a, and lower cutouts 273b and 274b. The cutouts 271-274b are arranged on the common electrode 270 corresponding to positions between the cutouts 91a, 91b, 92, and 94 of the neighboring pixel electrodes 190 as well as between the peripheral cutouts 91a and 91b and the leg of the pixel electrode 190. Furthermore, the respective cutouts 271-274b include at least one inclined portion extended parallel to the cutouts 91a, 91b, and 92 and the gap 94 of the pixel electrode 190.

The lower and upper cutouts 273a-274b include an inclined portion extended along the common electrode 270 from a position corresponding to the right side of the pixel electrode 190 toward the lower or the upper side thereof, and horizontal and vertical portions extended from positions corresponding to the respective ends of the inclined portion along the sides of the pixel electrode 190 while being overlapped with those sides and obtuse-angled against the inclined portion.

The first middle cutout 271 has a central horizontal portion on the common electrode 270 horizontally extended from a position corresponding to the left side of the pixel electrode 190, a pair of inclined portions extended from positions corresponding to the end of the central horizontal portion toward the left side of the pixel electrode 190 while being inclined with respect to the central horizontal portion, and vertical end portions extended from positions corresponding to the ends of the inclined portions while being overlapped with the left side of the pixel electrode 190 and obtuse-angled against the inclined portions. The second middle cutout 272 includes a vertical portion on the common electrode 270 extended along positions corresponding to the right side of the second sub-pixel electrode 190b while being overlapped therewith, a pair of inclined portions extended from positions corresponding

to the respective ends of the vertical portion toward the left side of the pixel electrode 190, and vertical end portions extended from positions corresponding to the ends of the inclined portions along the left side of the second sub-pixel electrode 190b while being overlapped therewith and obtuse-angled against the inclined portions.

Triangle-shaped notches are formed at the inclined portions of the cutouts 271-274b. Alternatively, each notch may be formed in the shape of a rectangle, a trapezoid, or a semi-circle, and may be concave or convex. The notches determine the alignment of the liquid crystal molecules 3 located at the periphery of the region corresponding to the cutouts 271-274b.

While a particular arrangement has been illustrated and described, the number of the cutouts 271-274b may be varied depending upon design factors, and the light blocking member 220 may be overlapped with the cutouts 271-274b to prevent the leakage of light around the cutouts 271-274b.

As the same common voltage is applied to the common electrode 270 and the shielding electrode 88, no electric field exists between the common electrode 270 and the shielding electrode 88. Accordingly, the liquid crystal molecules disposed between the common electrode 270 and the shielding electrode 88 continuously hold the initial vertical alignment state thereof, and the light incident thereto is intercepted.

An alignment layer 21 is coated on the common electrode 270 and the cover layer 250 to align the liquid crystal layer 3. The alignment layer 21 may be a horizontal alignment layer.

Polarizing plates 12 and 22 are provided on the outer surfaces of the panels 100 and 200, and the light transmission axes of the two polarizing plates 12 and 22 proceed perpendicular to each other. One of the light transmission axes of the two polarizing plates 12 and 22 (or the light absorption axis thereof) proceeds in the horizontal direction. In the case of a reflection type of LCD, one of the two polarizing plates 12 and 22 may be omitted.

The liquid crystal layer 3 has negative dielectric anisotropy, and the liquid crystal molecules of the liquid crystal layer 3 have directors vertically aligned with respect to the surfaces of the two panels when there is no application of a voltage.

When a common voltage is applied to the common electrode 270 and a data voltage is applied to the pixel electrode 190, an electric field is generated nearly vertical to the surfaces of the panels 100 and 200. The cutouts 91a-94 and 271-274b of the electrodes 190 and 270 deform such an electric field, and form components vertical to the sides of the cutouts 91a-94 and 271-274b.

Accordingly, the electric field is inclined with respect to the direction vertical to the surfaces of the panels 100 and 200. The liquid crystal molecules are aligned in response to the electric field such that the directors thereof proceed vertical to the electric field. At this time, the electric fields formed around the sides of the cutouts 91a-94 and 271-274b and the pixel electrode 190 do not proceed parallel to the directors of the liquid crystal molecules, but are angled against them at a predetermined angle. Therefore, the liquid crystal molecules are rotated on the plane between the directors of the liquid crystal molecules and the electric fields in the direction with a short movement distance. Consequently, the sides of a set of the cutouts 91a-94 and 271-274b and the pixel electrode 190 partition the portion of the liquid crystal layer 3 placed on the pixel electrode 190 into a plurality of domains where the inclination directions of the liquid crystal molecules differ from each other, and hence the reference viewing angle is enlarged.

At least one of the cutouts **91a-94** and **271-274b** may be replaced by a protrusion or a hollowed portion, and the shape and arrangement of the cutouts **91a-94** and **271-274b** may be varied.

An exemplary gate shorting bar of the exemplary embodiment of the LCD according to the present invention will be further described with reference to FIGS. **7** and **8**.

FIG. **7** is a view of exemplary gate shorting bars of the exemplary embodiments of the LCD shown in FIG. **1**, and FIG. **8** is a cross-sectional view of the exemplary embodiment of the LCD taken along line VIII-VIII' of FIG. **7**.

Gate pads **PG1a-PGnb** are formed on the insulating substrate **110**, and gate extension lines **321a**, **321b**, **322a**, **322b**, . . . based on the same material as the gate lines **121a** and **121b** horizontally extend from the gate pads **PG1a-PGnb**. The gate pads **PG1a-PGnb** and gate extension lines **321a**, **321b**, **322a**, **322b**, . . . may be formed during the same manufacturing process as the gate lines **121a** and **121b**. The gate insulating layer **140** is formed thereon, and gate shorting bars **320a** and **320b** are formed on the gate insulating layer **140** with the same material as the data lines **171** while proceeding in the vertical direction. The gate shorting bars **320a** and **320b** may be formed during the same manufacturing process as the data lines **171**. The passivation layer **180** is formed on the gate shorting bars **320a** and **320b**.

Contact holes **351a**, **352a**, . . . exposing the first gate shorting bar **320a** and contact holes **351b**, **352b**, . . . exposing the second gate shorting bar **320b** are formed through the passivation layer **180**. Contact holes **361a**, **361b**, **362a**, **362b**, . . . exposing the gate extension lines **321a**, **321b**, **322a**, **322b**, . . . are formed through the passivation layer **180** and the gate insulating layer **140**.

Connectors **341a**, **341b**, **342a**, **342b**, . . . are formed on the passivation layer **180** with ITO or IZO. The connectors **341a**, **341b**, **342a**, **342b**, . . . may be formed during the same manufacturing process as forming the pixel electrodes **190**. The first connectors **341a**, **342a**, . . . physico-electrically connect the first gate shorting bar **320a** to the first gate extension lines **321a**, **322a**, . . . through the first contact holes **351a** and **361a**, **352a** and **362a**, . . . , respectively. The second connectors **341b**, **342b**, . . . physico-electrically connect the second gate shorting bar **320b** to the second gate extension lines **321b**, **322b**, . . . through the second contact holes **351b** and **361b**, **352b** and **362b**, . . . , respectively.

Meanwhile, the gate extension lines **321a**, **321b**, **322a**, **322b**, . . . may extend over the shorting bars **320a** and **320b** up to a static prevention subsidiary line (not shown), and be connected thereto.

An array test and a VI test of an exemplary embodiment of an LCD according to the present invention will be described with reference to FIGS. **9** and **10**.

FIG. **9** is an exemplary test waveform diagram for an exemplary embodiment of an LCD according to the present invention, and FIG. **10** illustrates the polarities of exemplary pixels of an exemplary embodiment of an LCD according to the present invention.

As shown in FIG. **9**, gate test signals **Vga** and **Vgb** are applied to the gate shorting bars **320a** and **320b** by taking **T2** as a cycle. The gate test signals **Vga** and **Vgb** involve a phase difference of 180° . A positive data voltage **V+** and a negative data voltage **V-** are alternately applied to the data shorting bars **310** by taking **T2** as a cycle. The positive and negative polarities indicate the polarities of the data voltages **Vdata** with respect to the common voltage **Vcom**, and the dimensions of the positive and the negative data voltages **V+** and **V-** are equal to each other, or at least substantially the same. In other words, the positive and negative data voltages **V+** and

V- each have the same, or at least substantially the same, amount of deviation from the common voltage **Vcom**. Under the application of a positive data voltage **V+**, the first gate test signal **Vga** is applied to turn on the first switching element **Qa**. While under the application of a negative data voltage **V-**, the second gate test signal **Vgb** is applied to turn on the second switching element **Qb**.

Then, as shown in FIG. **10**, a positive pixel voltage is charged at the first sub-pixel electrodes **190a**, and a negative pixel voltage at the second sub-pixel electrodes **190b**. The positive and negative pixel voltages are continuously sustained at the first and second sub-pixel electrodes **190a** and **190b**, respectively.

However, as shown in the pixel on the upper right side of FIG. **10**, positive and negative voltages are alternately charged at the first and second sub-pixel electrodes interposing a bridge **ST1** as with the voltage V_{PST1} shown in FIG. **9**. Accordingly, the bridge **ST1** shown in FIG. **10**, or any other bridge between the first and second sub-pixel electrodes at each pixel, can be easily identified by detecting the polarities of the respective sub-pixel electrodes through the array test.

Meanwhile, when the pulse width **T1** of the gate test signals **Vga** and **Vgb** is properly controlled to slow the charging speed of the data voltages, voltages smaller than the positive and negative data voltages **V+** and **V-** are charged at the first and second sub-pixel electrodes with the bridge. In other words, the dimension of the voltages charged at the first and second sub-pixel electrodes with the bridge is smaller than the dimension of the positive and negative data voltages **V+** and **V-**. However, as the positive and negative data voltages **V+** and **V-** are continuously applied to the normal first and second sub-pixel electrodes, the same voltages as the positive and negative data voltages **V+** and **V-** are sustained there. Accordingly, the bridge between the first and second sub-pixel electrodes **190a** and **190b** can be easily identified by detecting the pixels differentiated in brightness from other pixels through the VI test.

If a bridge is formed between the first sub-pixel electrode **190a** and the shielding electrode **88**, and a common voltage **Vcom** is applied to the shielding electrode **88**, then a normal positive pixel voltage is not charged at the first sub-pixel electrode **190a**. Accordingly, the presence of a bridge between the first sub-pixel electrode **190a** and the shielding electrode **88** can be easily identified through the array test and the VI test.

Another exemplary embodiment of an LCD and a test method thereof according to the present invention will be further described with reference to FIGS. **11** to **14**.

FIG. **11** is a schematic view of another exemplary embodiment of an LCD according to the present invention, and FIG. **12** is an amplified view of exemplary gate shorting bars of the exemplary embodiment of the LCD shown in FIG. **11**. FIG. **13** is a test waveform diagram for another exemplary embodiment of an LCD according to the present invention, and FIG. **14** illustrates the polarities of exemplary pixels of another exemplary embodiment of an LCD according to the present invention.

The exemplary embodiment of the LCD described with respect to FIGS. **11** to **14** is quite similar to the LCD according to the previous embodiment, and hence, only the portions different from those of the previous embodiment will be further described.

As shown in FIG. **11**, the portion of the LCD internal to the LX line is substantially the same as that of the LCD according to the previous embodiment. With the LCD according to the present embodiment, the shielding electrode **88** shown in FIG. **4** is omitted, and accordingly, the first and second pixel

electrodes **190a** and **190b** may be overlapped with the data line **171**, thereby enhancing the aperture ratio thereof.

Furthermore, the data shorting bar **310** according to the present embodiment is the same as that according to the previous embodiment. However, the LCD according to the present embodiment includes four gate shorting bars **420a-420d** connected to gate pads PG1a-PGnb, instead of two gate shorting bars **320a** and **320b** as in the previous embodiment.

The gate pads PG1a-PGnb are sequentially connected to the gate shorting bars **420a-420d** by fours. That is, the gate pads PG1a, PG1b, PG2a, and PG2b are connected to the gate shorting bars **420a**, **420b**, **420c**, and **420d** through gate extension lines **421a**, **421b**, **421c**, and **421d**, respectively. The next set of gate pads PG3a, . . . are connected to the gate shorting bars **420a**, **420b**, **420c**, and **420d** through the gate extension lines **422a**, . . . , respectively, in the same manner, and so on for the remainder of the gate pads PG.

As shown in FIG. 12, the interconnection structure of the gate shorting bars **420a-420d** and the gate extension lines are substantially the same as that of the gate shorting bars **320a** and **320b** and the gate extension lines shown in FIGS. 7 and 8 except that the number of gate shorting bars **420a-420d** is increased to four, and the connection order thereof with the gate pads PG1a-PGnb is differentiated. In other words, every fourth gate extension line is connected to the same gate shorting bar.

As shown in FIG. 13, gate test signals Vga-Vgd are applied to the gate shorting bars **420a-420d**, and thus to the gate lines, by taking T4 as a cycle. The gate test signals Vga-Vgd sequentially involve a phase difference of 90°. The positive data voltage V+ and the negative data voltage V- are alternately applied to the data shorting bar **310**, and thus to the data lines, by taking T4 as a cycle.

Under the application of a positive data voltage V+ to the data lines, the first and fourth gate test signals Vga and Vgd are applied to the gate lines to turn on the first switching elements Qa at the odd-numbered pixel rows and the second switching elements Qb at the even-numbered pixel rows, while under the application of a negative data voltage V- to the data lines, the second and third gate test signals Vgb and Vgc are applied to the gate lines to turn on the second switching elements Qb at the odd-numbered pixel rows and the first switching elements Qa at the even-numbered pixel rows.

Then, as shown in FIG. 14, a positive pixel voltage is charged at the first sub-pixel electrodes **190a** at the odd-numbered pixel rows, and a negative pixel voltage is charged at the second sub-pixel electrodes **190b** at the odd-numbered pixel rows. Furthermore, a negative pixel voltage is charged at the first sub-pixel electrodes **190a** at the even-numbered pixel rows, and a positive pixel voltage is charged at the second sub-pixel electrodes **190b** at the even-numbered pixel rows. The once-charged positive or negative pixel voltage is continuously sustained at the respective sub-pixel electrodes **190a** and **190b** that do not have any bridges interposed thereon.

However, as shown in the right top portion of FIG. 14, positive and negative voltages are alternately charged at the two first sub-pixel electrodes **190a** within adjacent pixels interposing a bridge ST2 as with the voltage V_{PST2} shown in FIG. 13. Furthermore, as shown in the right bottom of FIG. 14, positive and negative voltages are alternately charged at the first and second sub-pixel electrodes **190a** and **190b** within a same pixel interposing a bridge ST3 as with the voltage V_{PST3} shown in FIG. 13. Accordingly, the bridge ST3 as shown in FIG. 14, or any other bridge that may exist between the first and second sub-pixel electrodes **190a** and **190b** at each pixel, and the bridge ST2 as shown in FIG. 14, or

any other bridge that may exist between the two neighboring first sub-pixel electrodes **190a** can be easily identified by detecting the polarity of the respective sub-pixel electrodes through the array test.

When the pulse width T3 of the gate test signals Vga-Vgd is properly controlled to slow the charging speed of the data voltages, voltages smaller than the positive and negative data voltages V+ and V- are charged at the two first sub-pixel electrodes **190a** with the bridge, and voltages smaller than the positive and negative data voltages V+ and V- are also charged at the first and second sub-pixel electrodes **190a** and **190b** with the bridge. In other words, the dimension of the voltages charged at the first and second sub-pixel electrodes with the bridge is smaller than the dimension of the positive and negative data voltages V+ and V-. Accordingly, any bridge between the first sub-pixel electrodes **190a** and any bridge between the first and second sub-pixel electrodes **190a** and **190b** can be easily identified by detecting the pixels differentiated in brightness from other pixels through the VI test.

While it has been described that the exemplary embodiments of the LCD according to the present invention have one data shorting bar, it should be understood that the LCD may alternatively include a plurality of data shorting bars, for instance, two or three data shorting bars. As with the embodiments of the LCD that include the plurality of gate shorting bars, the array test and the VI test can also be made in the embodiments of the LCD having the plurality of data shorting bars.

Another exemplary embodiment of an LCD according to the present invention will now be described with reference to FIGS. 15 and 16.

FIG. 15 is a schematic view of another exemplary embodiment of an LCD according to the present invention, and FIG. 16 is an equivalent circuit diagram of an exemplary pixel of another exemplary embodiment of an LCD according to the present invention.

As shown in FIG. 15, an LCD includes a liquid crystal panel assembly, which includes, from the equivalent circuit perspective, a plurality of display signal lines G1-Gn and D1a-Dmb and a plurality of pixels PX connected to those display signal lines and arranged in the form of a matrix.

The display signal lines G1-Gn and D1a-Dmb include a plurality of gate lines G1-Gn for transmitting gate signals, and data lines D1a-Dmb for transmitting data signals. The gate lines G1-Gn extend in the pixel row direction substantially parallel to each other in a first direction, and the data lines D1a-Dmb extend in the pixel column direction substantially parallel to each other in a second direction. The first direction may be substantially perpendicular to the second direction.

The liquid crystal panel assembly includes gate pads PG1-PGn connected to the gate lines G1-Gn, respectively, and data pads PD1a-PDmb connected to the data lines D1a-Dmb, respectively, such that each gate line G1-Gn is connected to one gate pad PG and each data line D1a-Dmb is connected to one data pad PD. Gate and data shorting bars **320**, and **310a** and **310b** are connected to the gate lines G1-Gn and the data lines D1a-Dmb, respectively.

The gate shorting bar **320** is connected to the gate pads PG1, PG2, . . . through gate extension lines **321**, **322**, Accordingly, the respective gate lines G1-Gn are connected to each other via the gate shorting bar **320**. The gate shorting bar **320** may extend substantially perpendicular to the gate lines G1-Gn, and substantially parallel to the data lines D1a-Dmb.

The first data shorting bar **310a** is connected to the first data pads PD1a, PD2a, PD3a, . . . via the first data extension lines

311a, 312a, 313a, . . . , and the second data shorting bar 310b is connected to the second data pads PD1b, PD2b, . . . via the second data extension lines 311b, 312b, . . . Accordingly, the respective first data lines D1a-Dma are connected to each other via the data shorting bar 310a, and the respective second data lines D1b-Dmb are connected to each other via the data shorting bar 310b. The data shorting bars 310a and 310b may extend substantially perpendicular to the data lines D1a-Dmb, and substantially parallel to the gate lines G1-Gn.

Separate pads (not shown) are provided at the end portions of the gate shorting bar 320 and the data shorting bars 310a and 310b to apply various kinds of test signals, as will be further described below.

After the gate shorting bar 320 and the data shorting bars 310a and 310b undergo several tests, they are then removed along the LX line thereof. That is, elements within an interior of the LX periphery are retained for the LCD, and elements outside of the LX periphery, such as the gate shorting bar 320 and the data shorting bars 310a and 310b, are removed. Consequently, by removal of the shorting bars 320, 310a, and 310b, the gate lines G1-Gn are separated from the data lines D1a-Dmb. A gate driver (not shown) and a data driver (not shown) are connected to the gate and data pads PG1-PGn and PD1a-PDmb as external devices to apply gate and data signals to the gate and data lines G1-Gn and D1a-Dmb. However, in the case that the gate driver is integrated on the liquid crystal panel assembly, the gate pads may be omitted, and gate extension lines 321, 322, . . . extend from the gate driver.

FIG. 16 illustrates display signal lines and an equivalent circuit at one exemplary pixel PX. The display signal lines include gate lines indicated by GL, data lines indicated by DL_a and DL_b, and storage electrode lines SL proceeding substantially parallel to the gate lines GL. Thus, in contrast to the previous embodiments that included two gate lines GL_a and GL_b and a single data line DL per pixel, this embodiment includes a single gate line GL and a pair of data lines DL_a and DL_b per pixel.

The respective pixels PX include a pair of sub-pixels PX_c and PX_d, and the respective sub-pixels PX_c and PX_d include switching elements Q_c and Q_d connected to the relevant gate and data lines GL, and DL_a, and DL_b, and liquid crystal capacitors C_{Lc} and C_{Ld} and storage capacitors C_{STc} and C_{STd} connected to those switching elements. In an alternative embodiment, the storage capacitors C_{STc} and C_{STd} may be omitted, and in such a case, the storage electrode line SL is dispensed with.

As shown in FIGS. 15 and 16, all the gate lines GL are connected to the gate shorting bar 320, all the first data lines DL_a are connected to the first data shorting bar 310a, and all the second data lines DL_b are connected to the second data shorting bar 310b. Accordingly, the same signal can be applied to the respective first sub-pixels PX_c, and the same signal that is different from the signal applied to the first sub-pixels PX_c can be applied to the respective second sub-pixels PX_d.

As the respective sub-pixels PX_c and PX_d are substantially the same as the sub-pixels shown in FIG. 3, a detailed description thereof will be omitted.

The structure of the LCD will now be further described with reference to FIGS. 17 and 18.

FIG. 17 is a plan view of another exemplary embodiment of an LCD according to the present invention, and FIG. 18 is a cross-sectional view of the exemplary embodiments of the LCD taken along line XVIII-XVIII' of FIG. 17.

As shown in FIGS. 17 and 18, the LCD includes a lower panel 101, an upper panel 201 facing the lower panel 101, and a liquid crystal layer 3 disposed between those panels 101 and

201. The lower panel 101 may also be known as a TFT panel or first panel, and the upper panel 201 may also be known as a common electrode panel, a color filter panel, or a second panel.

First, the lower panel 101 will be described.

A plurality of gate lines 121 and a plurality of storage electrode lines 131a are formed on an insulating substrate 110 based on transparent glass or plastic.

The gate lines 121 extend horizontally, such as in a transverse or first direction, and are separated from each other to transmit gate signals. The respective gate lines 121 have a plurality of protrusions forming gate electrodes 124c and 124d, and a wide area end portion 129 for making a connection with other layers or external devices.

The storage electrode lines 131a also extend horizontally, substantially parallel to the gate lines 121, and have a plurality of protrusions forming storage electrodes 133a and 133b. The storage electrodes 133a and 133b may be rectangular shaped and symmetrical to the storage electrode line 131a.

A gate insulating layer 140 is formed on the gate lines 121 and the storage electrode lines 131a and may be further formed over exposed portions of the insulating substrate 110. The gate insulating layer 140 may be made with silicon nitride (SiN_x) or the like.

A plurality of island-shaped semiconductors 154c, 154d, 156b, and 157b are formed on the gate insulating layer 140 with hydrogenated a-Si or polycrystalline silicon. The semiconductors 154c and 154d are placed on the gate electrodes 124c and 124d, respectively.

A plurality of island-shaped ohmic contacts 163c, 163d, 165c, 165d, 166b, and 167 are formed on the semiconductors 154c, 154d, 156b, and 157b with n+ hydrogenated a-Si where n-type impurities such as silicide and phosphorous are doped at a high concentration. Pairs of the ohmic contacts 163c and 165c and ohmic contacts 163d and 165d are placed on the semiconductors 154c and 154d, and the other ohmic contacts 166b and 167 are placed on the semiconductors 156b and 157b, respectively.

A plurality of data lines 171a and 171b, and drain electrodes 175c and 175d separated from the data lines 171a and 171b are formed on the gate insulating layer 140 and the ohmic contacts 163c, 163d, 165c, 165d, 166b, and 167.

The data lines 171a and 171b extend vertically, such as in a longitudinal or second direction, such that they cross the gate lines 121 and storage electrode lines 131a to transmit data voltages. The data lines 171a and 171b are insulated from the gate lines 121 by the gate insulating layer 140 disposed there between. The data lines 171a and 171b include a plurality of source electrodes 173c and 173d and end portions 179a and 179b with an enlarged width to make a connection with other layers or external devices.

The first and second drain electrodes 175c and 175d are separated from the data lines 171a and 171b, and face the source electrodes 173c and 173d around the gate electrodes 124c and 124d, respectively. The first and second drain electrodes 175c and 175d have bar-shaped end portions placed over the semiconductors 154c and 154d, and wide area extensions 177c and 177d extended from the bar-shaped end portions and overlapped with the storage electrodes 133a and 133b. The bar-shaped end portions of the drain electrodes 175c and 175d are partially surrounded by the U-bent source electrodes 173c and 173d.

The first and second gate electrodes 124c and 124d, the first and second source electrodes 173c and 173d, and the first and second drain electrodes 175c and 175d form first and second TFTs Q_c and Q_d together with the semiconductors 154c and 154d. The channels of the TFTs Q_c and Q_d are formed on the

semiconductors **154c** and **154d** between the first and second source electrodes **173c** and **173d** and the first and second drain electrodes **175c** and **175d**, and between the ohmic contacts **163c**, **163d** and **165c**, **165d**.

The ohmic contacts **163c**, **163d**, **165c**, **165d**, **166b**, and **167** are only interposed between the underlying semiconductors **154c**, **154d**, **156b**, and **157b** and the overlying data lines **171a** and **171b** and drain electrodes **175c** and **175d** to lower the contact resistance therebetween. The island-shaped semiconductors **154c** and **154d** have portions exposed through the source electrodes **173c** and **173d** and the drain electrodes **175c** and **175d**, and the semiconductors **156b** and **157b** smooth the profile on the gate lines **121** and the storage electrode lines **131a** to thereby prevent the data lines **171a** and **171b** and the drain electrodes **175c** and **175d** from being cut.

A passivation layer **180** is formed on the data lines **171a** and **171b**, the drain electrodes **175c** and **175d**, and the exposed portions of the semiconductors **154c** and **154d**. The passivation layer **180** may be further formed on exposed portions of the gate insulating layer **140** as shown.

A plurality of contact holes **185c**, **185d**, **182a**, and **182b** are formed through the passivation layer **180** to expose the extensions **177c** and **177d** of the drain electrodes **175c** and **175d** and end portions **179a** and **179b** of the data lines **171a** and **171b**, respectively. A plurality of contact holes **181** are formed through the passivation layer **180** and the gate insulating layer **140** to expose end portions **129** of the gate lines **121**.

A plurality of pixel electrodes **191** with first and second sub-pixel electrodes **191a** and **191b**, a plurality of shielding electrodes **88a**, and a plurality of subsidiary contacts (contact assistants) **81**, **82a**, and **82b** are formed on the passivation layer **180**. The plurality of pixel electrodes **191**, plurality of shielding electrodes **88a**, and plurality of subsidiary contacts **81**, **82a**, and **82b** may be formed with a transparent conductive material such as ITO and IZO, or a reflective conductive material such as aluminum for use in a reflective LCD.

The first and second sub-pixel electrodes **191a** and **191b** are physico-electrically connected to the first and second drain electrodes **175c** and **175d** through the contact holes **185c** and **185d** to receive data voltages from the first and second drain electrodes **175c** and **175d**. Predetermined voltages different from each other are applied to a pair of sub-pixel electrodes **191a** and **191b** with respect to one input image signal, and the dimensions of the voltages may be determined depending upon the dimensions and shape of the sub-pixel electrodes **191a** and **191b**. Furthermore, the areas of the sub-pixel electrodes **191a** and **191b** may differ from each other. The second sub-pixel electrode **191b** receives a higher voltage compared to the first sub-pixel electrode **191a**, and is smaller in area than the first sub-pixel electrode **191a**.

The sub-pixel electrodes **191a** and **191b** receiving the data voltage generate an electric field in association with the common electrode **270** of the opposing panel **200** supplied with a common voltage, to thereby determine the alignment of the liquid crystal molecules of the liquid crystal layer **3** between the two electrodes **191** and **270**.

The respective sub-pixel electrodes **191a** and **191b** and the common electrode **270** form liquid crystal capacitors C_{LCc} and C_{LCd} , and sustain the applied voltage even after the TFTs Qc and Qd turn off. The storage capacitors C_{STc} and C_{STd} connected to the liquid crystal capacitors C_{LCc} and C_{LCd} in parallel to reinforce the voltage storage capacity are formed by overlapping the first and second sub-pixel electrodes **191a**

and **191b** and the extensions **177c** and **177d** of the drain electrodes **175c** and **175d** connected thereto with the storage electrodes **133a** and **133b**.

A pair of first and second sub-pixel electrodes **191a** and **191b** forming a pixel electrode **191** engage with each other while interposing a gap **93** therebetween, and the pixel electrode **191** is roughly outlined as a rectangle. The second sub-pixel electrode **191b** is roughly formed as a rotated equilateral trapezoid having a trapezoid-hollowed bottom side, and is mostly surrounded by the first sub-pixel electrode **191a**, that is, the second sub-pixel electrode **191b** is nested within the first sub-pixel electrode **191a**. The first sub-pixel electrode **191a** has an upper trapezoid portion, a lower trapezoid portion, and a middle trapezoid portion, which are connected to each other at the left side thereof. The middle trapezoid portion of the first sub-pixel electrode **191a** is fitted into the hollowed bottom side of the second sub-pixel electrode **191b**. The gap **93** between the first and second sub-pixel electrodes **191a** and **191b** roughly has two pairs of upper and lower inclined portions angled against the gate line **121** at roughly 45° with even widths, and three vertical portions substantially with even widths. For explanatory convenience, the gap **93** may also be referred to as a cutout.

The first sub-pixel electrode **191a** has cutouts **96a**, **96b**, **97a**, and **97b** proceeding from the top side of the upper trapezoid portion and the bottom side of the lower trapezoid portion toward the right side thereof. The first sub-pixel electrode **191a** has cutouts **91** and **92a** proceeding along the storage electrode line **131a**, and the cutouts **91** and **92a** have a horizontal portion horizontally proceeding from the center thereof and a pair of legs angled against the storage electrode line **131a** at about 45°. The second sub-pixel electrode **191b** has cutouts **94a** and **94b** proceeding from the left side to the right side. The cutouts **91**, **92a**, **94a**, **94b**, **96a**, **96b**, **97a**, and **97b** are inversion-symmetrical to the storage electrode line **131a**, and extend substantially perpendicular or parallel to each other while being angled against the gate line **121** at about 45°. That is, cutouts on an upper half of the pixel electrode **191** are arranged parallel to each other, cutouts on a lower half of the pixel electrode **191** are arranged parallel to each other, and cutouts on the upper half are arranged perpendicular to cutouts on the lower half. The upper half and the lower half of the pixel electrode **191** are partitioned into eight regions by way of the cutouts **91-97b**.

While a particular arrangement has been illustrated and described, the number of division regions or cutouts may be varied depending on design factors such as pixel size, the length ratio of the horizontal to the vertical sides of the pixel electrode **191**, and the kinds or characteristics of the liquid crystal layer **3**.

Shielding electrodes **88a** have vertical portions proceeding along the data lines **171a** and **171b**, and horizontal portions proceeding along the gate lines **121**. The vertical portions completely cover the data lines **171a** and **171b**, and the horizontal portions completely cover the gate lines **121**.

The shielding electrodes **88a** shield the electric field between the data lines **171a** and **171b** and the pixel electrode **191** as well as between the data lines **171a** and **171b** and the common electrode **270** so that voltage distortion of the pixel electrode **191** and signal delay of the data voltages transmitted by the data lines **171a** and **171b** are reduced. Furthermore, the pixel electrode **191** and the shielding electrode **88a** should be spaced apart from each other by a distance to prevent short-circuiting thereof. Consequently, as the pixel electrode **191** extends far enough from the data lines **171a** and **171b** and the gate line **121**, the parasitic capacitance therebetween is reduced.

The subsidiary contacts **81**, **82a**, and **82b** are connected to the end portions **129** of the gate lines **121** and the end portions **179a** and **179b** of the data lines **171a** and **171b**, respectively. The subsidiary contacts **81**, **82a**, and **82b** serve to reinforce the adhesion between the exposed end portions **129** of the gate lines **121** and the exposed end portions **179a** and **179b** of the data lines **171a** and **171b** and external devices, and protect them.

An alignment layer **11** is formed on the pixel electrode **191**, the subsidiary contacts **81**, **82a**, and **82b**, and the passivation layer **180** to align the liquid crystal layer **3**.

The upper panel **201** will now be described.

A light blocking member **220**, also termed a black matrix, a plurality of color filters **230**, a cover layer **250**, and a common electrode **270** are sequentially formed on an insulating substrate **210** based on transparent glass or plastic.

The common electrode **270** has multiple sets of cutouts **71**, **72**, **73a**, **74a**, **75c**, **75d**, **76c**, **76d**, **77a**, **77b**, **78a**, and **78b**.

Each set of the cutouts **71-78** faces one pixel electrode **191**, and includes middle cutouts **71**, **72**, **73a**, and **74a**, upper cutouts **75c**, **76c**, **77a**, and **78a**, and lower cutouts **75d**, **76d**, **77b**, and **78b**. The cutouts **71-78b** are arranged on the common electrode **270** corresponding to positions at the left-sided center of the pixel electrode **191**, between the neighboring cutouts of the pixel electrode **191**, and between the outermost cutouts **97a** and **97b** and the corners of the pixel electrode **191**. Furthermore, the cutouts **72-78b** include at least one inclined portion proceeding parallel to the cutouts **91-97b** of the pixel electrode **191**.

The lower and upper cutouts **75c-78b** include inclined portions proceeding along the common electrode **270** from positions corresponding to the right side of the pixel electrode **191** toward the bottom or top side, and horizontal and vertical portions proceeding from positions corresponding to the respective ends of the inclined portions along the sides of the pixel electrode **191** while being overlapped therewith and obtuse-angled against the inclined portions.

The first middle cutout **71** has a vertical portion on the common electrode **270** extending along a position corresponding to the left side of the pixel electrode **191** while being overlapped therewith, and a horizontal portion extending from the center of the vertical portion along the storage electrode line **131a**. The second and third middle cutouts **72** and **73a** include a horizontal portion on the common electrode **270** extending along a position corresponding to the storage electrode line **131a**, a pair of inclined portions extending from the horizontal portion toward a position corresponding to the left side of the pixel electrode **191** oblique to the storage electrode line **131a**, and vertical end portions extending from the ends of the inclined portions along positions corresponding to the left side of the pixel electrode **191** while being overlapped therewith and obtuse-angled against the inclined portions. The fourth middle cutout **74a** includes a vertical portion on the common electrode **270** extending along a position corresponding to the right side of the pixel electrode **191** while being overlapped therewith, a pair of inclined portions extending from the respective ends of the vertical portion toward positions corresponding to the left side of the pixel electrode **191**, and vertical end portions extending from the ends of the inclined portions along positions on the common electrode **270** corresponding to the left side of the second sub-pixel electrode **191b** while being overlapped therewith and obtuse-angled against the inclined portions.

Triangle-shaped notches are formed at the inclined portions of the cutouts **72-77b**. Alternatively, the notches may be formed with various shapes such as a rectangle, a trapezoid, and a semicircle, and with a convex or concave shape.

While a particular arrangement has been illustrated and described, the number of the cutouts on the common electrode **270** may be varied depending upon design factors.

An alignment layer **21** is formed on the common electrode **270** and the cover layer **250** to align the liquid crystal layer **3**.

Polarizing plates **12** and **22** are attached to the outer surfaces of the display panels **101** and **201**. In the case of a reflection type of LCD, one of the two polarizing plates **12** and **22** may be omitted.

Many features of the previous embodiments of the LCD described with reference to FIGS. **4** to **6** may also be applied to the LCD shown in FIGS. **17** and **18**.

Exemplary data shorting bars according to the present embodiment will be further described with reference to FIGS. **19** and **20**.

FIG. **19** is an amplified view of exemplary data shorting bars of the exemplary embodiment of the LCD shown in FIG. **15**, and FIG. **20** is a cross-sectional view of the exemplary embodiment of the LCD taken along line XX-XX' of FIG. **19**.

Data shorting bars **310a** and **310b** are formed on the insulating substrate **110** of the same material as the gate line **121**, and the gate insulating layer **140** is formed thereon. The data shorting bars **310a** and **310b** may be formed during the same manufacturing process as the gate line **121**. Data pads PD1a-PDmb are formed on the gate insulating layer **140**, and data extension lines **311a**, **311b**, **312a**, **312b**, . . . vertically extend from the data pads with the same material as the data lines **171a** and **171b**. The data pads PD1a-PDmb and data extension lines **311a**, **311b**, **312a**, **312b**, . . . may be formed during the same manufacturing process as the data lines **171a** and **171b**. The passivation layer **180** is formed on the data extension lines **311a**, **311b**, **312a**, **312b**, . . .

Contact holes **381a**, **381b**, **382a**, **382b**, . . . are formed through the passivation layer **180** to expose the data extension lines **311a**, **311b**, **312a**, **312b**, Contact holes **391a**, **392a**, . . . exposing the first data shorting bar **310a** and contact holes **391b**, **392b**, . . . exposing the second data shorting bar **310b** are formed through the passivation layer **180** and the gate insulating layer **140**.

Connectors **371a**, **371b**, **372a**, **372b**, . . . are formed on the passivation layer **180** with ITO or IZO. The connectors **371a**, **371b**, **372a**, **372b**, . . . may be formed during the same manufacturing process as forming the pixel electrodes **191**. The first connectors **371a**, **372a**, . . . physico-electrically interconnect the first data shorting bar **310a** and the data extension lines **311a**, **312a**, . . . through the first contact holes **381a**, **391a**, **382a**, **392a**, . . . , and the second connectors **371b**, **372b**, . . . physico-electrically interconnect the second data shorting bar **310b** and the data extension lines **311b**, **312b**, . . . through the second contact holes **381b**, **391b**, **382b**, **392b**, . . . , respectively.

Meanwhile, the data extension lines **311a**, **311b**, **312a**, **312b**, . . . may extend over the data shorting bars **310a** and **310b** such that they are connected to an antistatic subsidiary line (not shown).

A VI test for an exemplary embodiment of an LCD according to the present invention will now be described with reference to FIGS. **21** and **22**.

FIG. **21** is an exemplary test waveform diagram for another exemplary embodiment of an LCD according to the present invention, and FIG. **22** illustrates the pixel polarities of another exemplary embodiment of an LCD according to the present invention.

As shown in FIG. **21**, a gate test signal V_g is applied to a gate shorting bar **320** with a cycle of T6. A positive data voltage V_+ is applied to a first data shorting bar **310a**, and a negative data voltage V_- is applied to a second data shorting

bar **310b**. The dimensions of the positive and negative data voltages $V+$ and $V-$ are equal to each other, or at least substantially the same. In other words, the positive and negative data voltages $V+$ and $V-$ each have the same, or at least substantially the same, amount of deviation from the common voltage V_{com} . With the application of the gate test signal V_g , the switching elements Q_c and Q_d turn on so that a positive pixel voltage is charged at a first sub-pixel electrode **191a**, and a negative pixel voltage is charged at a second sub-pixel electrode **191b**. The positive and negative pixel voltages are continuously sustained at the first and second sub-pixel electrodes **191a** and **191b**.

However, as shown in FIG. 22, in the case that a bridge **ST4** is formed between the data lines **D2b** and **D3a**, a voltage V_{PST4} (for example, a common voltage) that is smaller than the positive and negative data voltages $V+$ and $V-$ is applied to the first and second sub-pixel electrodes connected thereto. That is, the sub-pixel electrodes connected to the data lines **D2b** and **D3a** are applied with the voltage V_{PST4} , such as the common voltage, which has a smaller dimension than the positive and negative data voltages $V+$ and $V-$ because it does not deviate from the common voltage as much, if at all, as the positive and negative data voltages $V+$ and $V-$ deviate from the common voltage. Accordingly, the bridge between the first and second data lines **171a** and **171b** can be easily identified by detecting the pixel column with a brightness different from that of the neighboring column through the VI test.

Furthermore, even when a bridge **ST5** is formed between the first and second sub-pixel electrodes **191a** and **191b**, a voltage V_{PST5} that is smaller than the positive and negative data voltages $V+$ and $V-$ is charged at the sub-pixel electrodes. Accordingly, the bridge between the first and second sub-pixel electrodes **191a** and **191b** can be easily identified by detecting the pixel with a brightness different from that of the neighboring pixel through the VI test.

As described above, with the inventive structure, the gate lines connected to the respective sub-pixels are connected to two or four gate shorting bars, and the array test and the VI test are done. In this way, a bridge between respective sub-pixel electrode neighbors can be easily detected.

Furthermore, the data lines connected to the respective sub-pixels are connected to two data shorting bars, and the VI test is done. In this way, a bridge between respective data line neighbors and a bridge between respective sub-pixel electrode neighbors can be easily detected.

While the present invention has been described in detail with reference to the preferred embodiments, those skilled in the art will appreciate that various modifications and substitutions can be made thereto without departing from the spirit and scope of the present invention as set forth in the appended claims.

What is claimed is:

1. A method of testing a liquid crystal display including a plurality of pixel electrodes having first and second sub-pixel electrodes, first and second switching elements connected to the first and second sub-pixel electrodes, respectively, first and second gate lines connected to the first and second switching elements, respectively, and a data line connected to the first and second switching elements, the method comprising:

providing first and second gate shorting bars connected to the first and second gate lines, respectively;
 providing a data shorting bar connected to the data line;
 applying a positive data voltage to the data shorting bar;
 applying a first gate test signal to the first gate shorting bar to apply the positive data voltage to the first sub-pixel electrode;

applying a negative data voltage to the data shorting bar; and

applying a second gate test signal to the second gate shorting bar to apply the negative data voltage to the second sub-pixel electrode.

2. The method of claim 1, further comprising detecting polarities of the first and second sub-pixel electrodes.

3. The method of claim 2, wherein detecting polarities of the first and second sub-pixel electrodes includes performing an array test.

4. The method of claim 1, further comprising identifying existence of a bridge between the first and second sub-pixel electrodes.

5. The method of claim 4, wherein positive and negative pixel voltages of the first and second sub-pixel electrodes having a bridge are not continuously sustained under application of positive and negative data voltages.

6. The method of claim 1, wherein the positive and negative data voltages have substantially same dimensions.

7. The method of claim 6, further comprising detecting uniformity of luminance of the liquid crystal display.

8. The method of claim 7, wherein detecting uniformity of luminance includes performing a visual inspection test.

9. The method of claim 7, further comprising identifying existence of a bridge between the first and second sub-pixel electrodes when brightness of a pixel having the first and second sub-pixel electrodes with a bridge is differentiated in brightness from other pixels not having a bridge.

10. The method of claim 7, further comprising identifying existence of a bridge between the first sub-pixel electrode and a shielding electrode.

11. The method of claim 1, further comprising separating the first and second gate shorting bars from the first and second gate lines, and separating the data shorting bar from the data line.

12. A method of testing a liquid crystal display including a plurality of pixel electrodes having first and second sub-pixel electrodes, first and second switching elements connected to the first and second sub-pixel electrodes, respectively, first and second gate lines connected to the first and second switching elements, respectively, and a data line connected to the first and second switching elements, the method comprising:

providing first and second gate shorting bars connected to the first and second gate lines at odd-numbered pixel rows, respectively;

providing third and fourth gate shorting bars connected to the first and second gate lines at even-numbered pixel rows, respectively;

providing a data shorting bar connected to the data line; applying a positive data voltage to the data shorting bar; applying a first gate test signal to the first gate shorting bar to apply the positive data voltage to the first sub-pixel electrode at the odd-numbered pixel rows;

applying a negative data voltage to the data shorting bar; applying second and third gate test signals to the second and third gate shorting bars to apply the negative data voltage to the second sub-pixel electrode at the odd-numbered pixel rows and to the first sub-pixel electrode at the even-numbered pixel rows; and

applying a fourth gate test signal to the fourth gate shorting bar to apply the positive data voltage to the second sub-pixel electrode at the even-numbered pixel rows.

13. The method of claim 12, further comprising detecting polarities of the first and second sub-pixel electrodes.

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14. The method of claim 12, further comprising identifying existence of a bridge between the first and second sub-pixel electrodes.

15. The method of claim 12, further comprising identifying existence of a bridge between the first sub-pixel electrodes of adjacent pixels. 5

16. The method of claim 12, wherein the positive and negative data voltages have substantially same dimensions.

17. The method of claim 16, further comprising detecting uniformity of luminance of the liquid crystal display. 10

18. The method of claim 12, further comprising separating the first and second gate shorting bars from the first and second gate lines at the odd-numbered pixel rows; separating the third and fourth gate shorting bars from the first and second gate lines at the even-numbered pixel rows; and separating the data shorting bars from the data line. 15

19. A method of testing a liquid crystal display including a plurality of pixel electrodes having first and second sub-pixel electrodes, first and second switching elements connected to the first and second sub-pixel electrodes, respectively, a gate line connected to the first and second switching elements, and first and second data lines connected to the first and second switching elements, respectively, the method comprising: 20

providing first and second data shorting bars connected to the first and second data lines;

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providing a gate shorting bar connected to the gate line; applying a positive data voltage to the first data shorting bar;

applying a negative data voltage to the second data shorting bar; and

applying a gate test signal to the gate shorting bar to apply the positive data voltage to the first sub-pixel electrode and to apply the negative data voltage to the second sub-pixel electrode.

20. The method of claim 19, further comprising detecting uniformity of luminance of the liquid crystal display.

21. The method of claim 19, further comprising identifying existence of a bridge between the first and second data lines.

22. The method of claim 19, further comprising identifying existence of a bridge between the first and second sub-pixel electrodes.

23. The method of claim 19, wherein the positive and negative data voltages have substantially same dimension.

24. The method of claim 19, further comprising separating the first and second data shorting bars from the first and second data lines, and separating the gate shorting bar from the gate line.

* * * * *

专利名称(译)	液晶显示器及其测试方法		
公开(公告)号	US7847872	公开(公告)日	2010-12-07
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[标]申请(专利权)人(译)	三星电子株式会社		
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摘要(译)

一种液晶显示器，包括以矩阵排列的多个像素电极，并且具有彼此尺寸不同的第一和第二子像素电极。第一和第二开关元件分别连接到第一和第二子像素电极。第一和第二栅极线分别连接到第一和第二开关元件。数据线连接到第一和第二开关元件以传输数据电压。第一和第二栅极短路棒分别连接到第一和第二栅极线。连接到各个子像素的栅极线连接到两个或四个栅极短路棒，以允许阵列测试和视觉检查测试，从而以简化的方式检测各个子像素电极邻居之间的桥。

